Measurement Report for Device, P1 GSM850_GPRS 2TS_Right Cheek_Ch 251

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, HSL	CHEEK, 0.00	GSM 850	GSM, 10024-DAC	848.800, 251	9.70	0.895	40.3

Hardware Setup

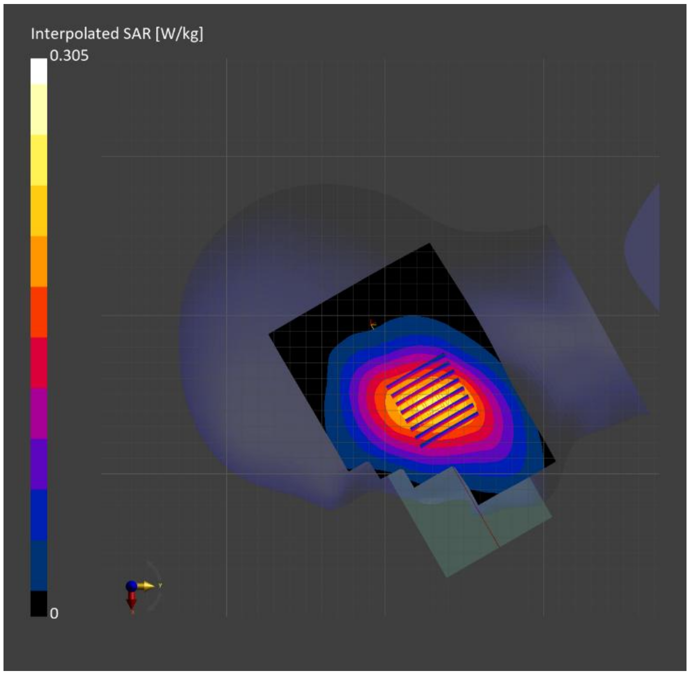
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-May-29	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-29	2025-05-29
psSAR1g [W/kg]	0.212	0.229
psSAR10g [W/kg]	0.146	0.181
Power Drift [dB]	-0.04	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		89.2
Dist 3dB Peak [mm]		26.4



Measurement Report for Device, P2 GSM1900_GPRS 2TS_Left Cheek_Ch 512

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, HSL	CHEEK, 0.00	PCS 1900	GSM, 10024-DAC	1850.200, 512	7.77	1.38	39.8

Hardware Setup

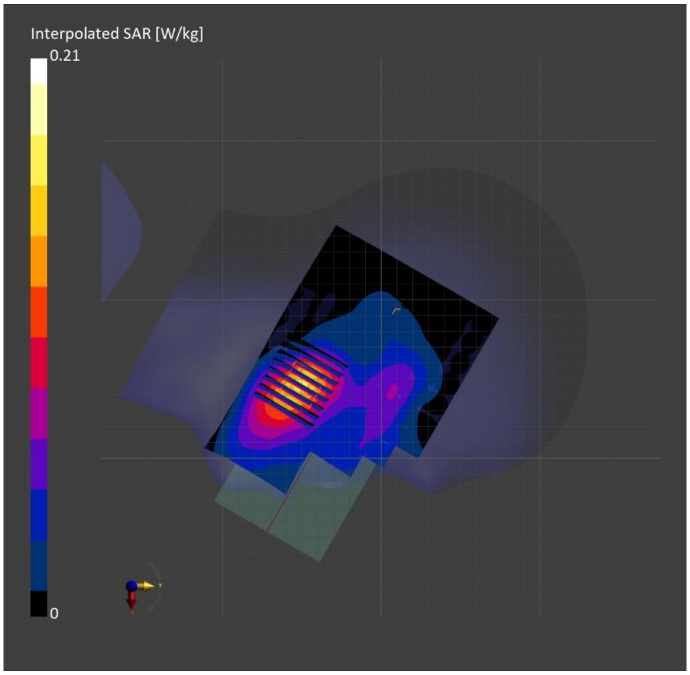
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-02	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-02	2025-06-02
psSAR1g [W/kg]	0.132	0.142
psSAR10g [W/kg]	0.079	0.093
Power Drift [dB]	-0.13	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		87.7
Dist 3dB Peak [mm]		13.8



Measurement Report for Device, P3 WCDMA II_RMC12.2K_Left Cheek_Ch 9400

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, HSL	CHEEK, 0.00	Band 2	WCDMA, 10011-CAC	1880.000, 9400	7.77	1.39	39.7

Hardware Setup

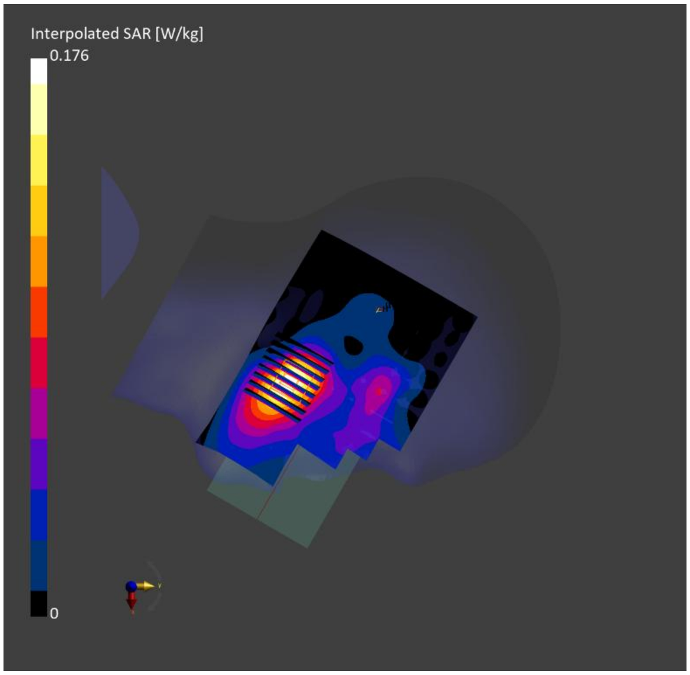
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000 , 2025-Jun-02	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-02	2025-06-02
psSAR1g [W/kg]	0.105	0.113
psSAR10g [W/kg]	0.061	0.070
Power Drift [dB]	-0.01	0.08
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		87.2
Dist 3dB Peak [mm]		12.1



Measurement Report for Device, P4 WCDMA V_RMC12.2K_Right Cheek_Ch 4233

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, HSL	CHEEK, 0.00	Band 5	WCDMA, 10011-CAC	846.600, 4233	9.70	0.894	40.3

Hardware Setup

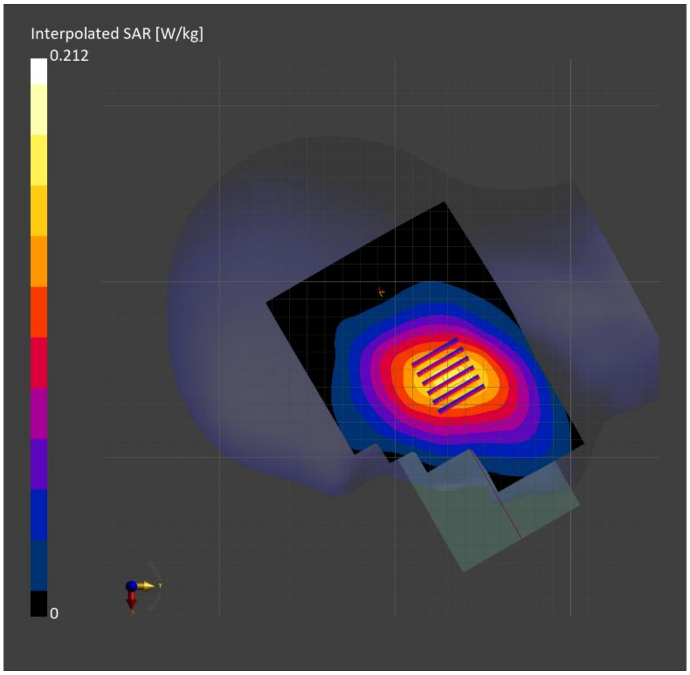
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-May-29	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-29	2025-05-29
psSAR1g [W/kg]	0.148	0.156
psSAR10g [W/kg]	0.101	0.122
Power Drift [dB]	-0.02	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		88.6
Dist 3dB Peak [mm]		> 15.0



Measurement Report for Device, P5 LTE 2_QPSK20M_Left Cheek_Ch 18700_1RB_OS99

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, **HSL**	CHEEK, 0.00	Band 2	LTE-FDD, 10169-CAF	1860.000, 18700	7.77	1.39	39.8

Hardware Setup

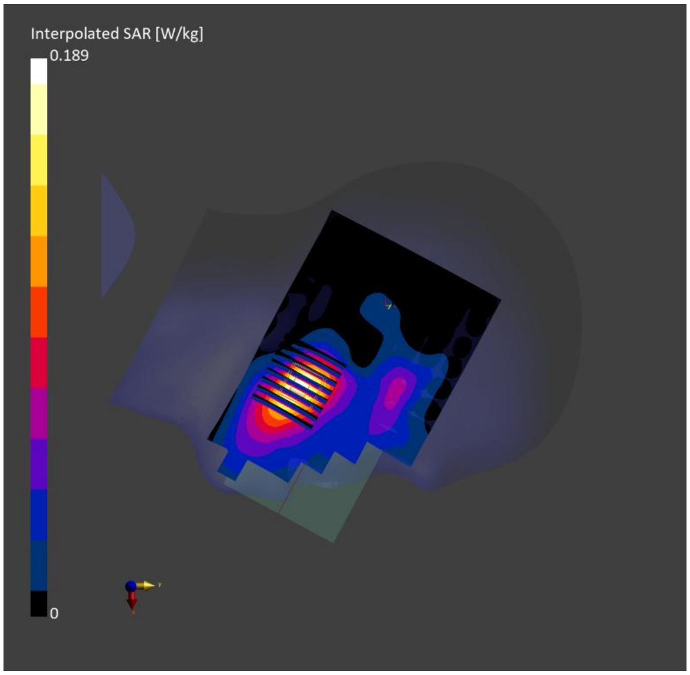
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-02	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-02	2025-06-02
psSAR1g [W/kg]	0.109	0.119
psSAR10g [W/kg]	0.063	0.073
Power Drift [dB]	-0.08	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.8
Dist 3dB Peak [mm]		11.0



Measurement Report for Device, P6 LTE 66_QPSK20M_Right Cheek_Ch 132572_1RB_OS99

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, HSL	CHEEK, 0.00	Band 66	LTE-FDD, 10169-CAF	1770.000, 132572	8.40	1.34	40.0

Hardware Setup

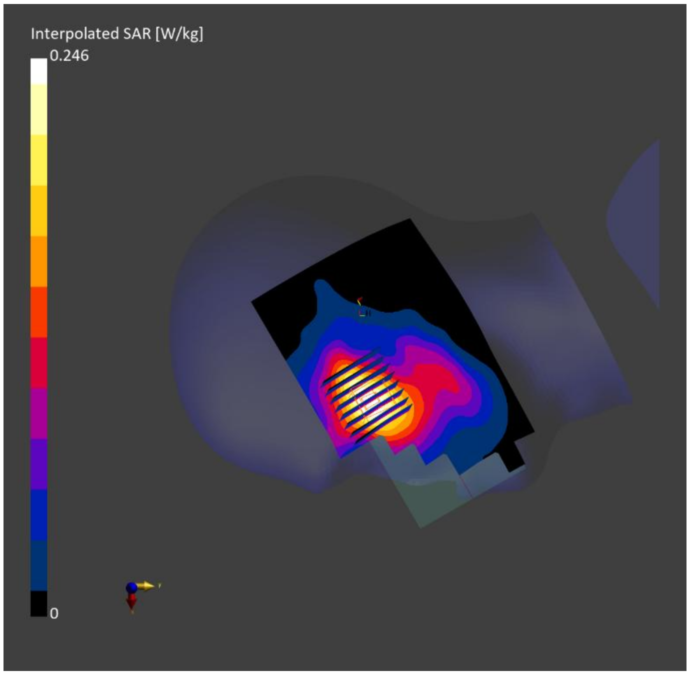
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-03	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-03	2025-06-03
psSAR1g [W/kg]	0.143	0.161
psSAR10g [W/kg]	0.088	0.106
Power Drift [dB]	0.01	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		86.8
Dist 3dB Peak [mm]		13.3



Measurement Report for Device, P7 LTE 5_QPSK10M_Right Cheek_Ch 20525_1RB_OS24

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, HSL	CHEEK, 0.00	Band 5	LTE-FDD, 10175-CAH	836.500, 20525	9.70	0.891	40.4

Hardware Setup

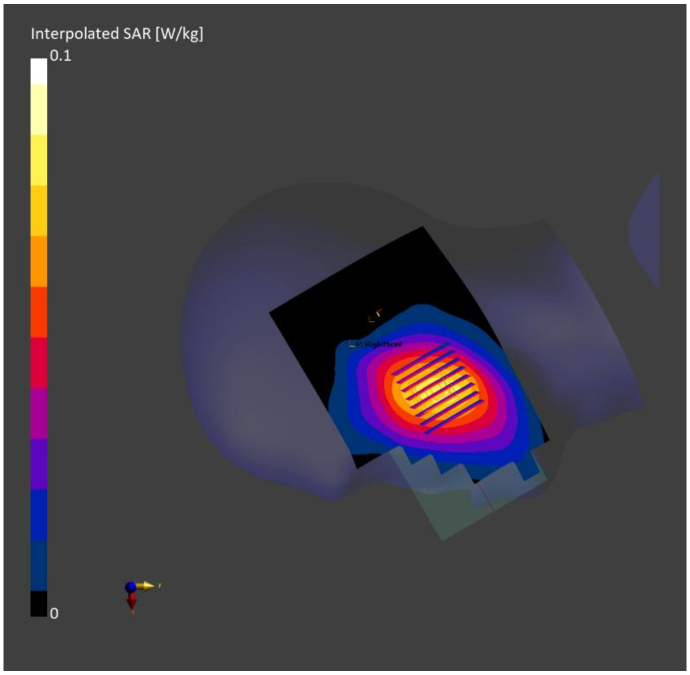
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-May-29	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-29	2025-05-29
psSAR1g [W/kg]	0.071	0.072
psSAR10g [W/kg]	0.049	0.058
Power Drift [dB]	-0.06	0.07
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		88.3
Dist 3dB Peak [mm]		21.5



Measurement Report for Device, P8 LTE 7_QPSK20M_Right Cheek_Ch 21100_1RB_OS99

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, **HSL**	CHEEK, 0.00	Band 7	LTE-FDD, 10169-CAF	2535.000, 21100	7.64	1.85	39.8

Hardware Setup

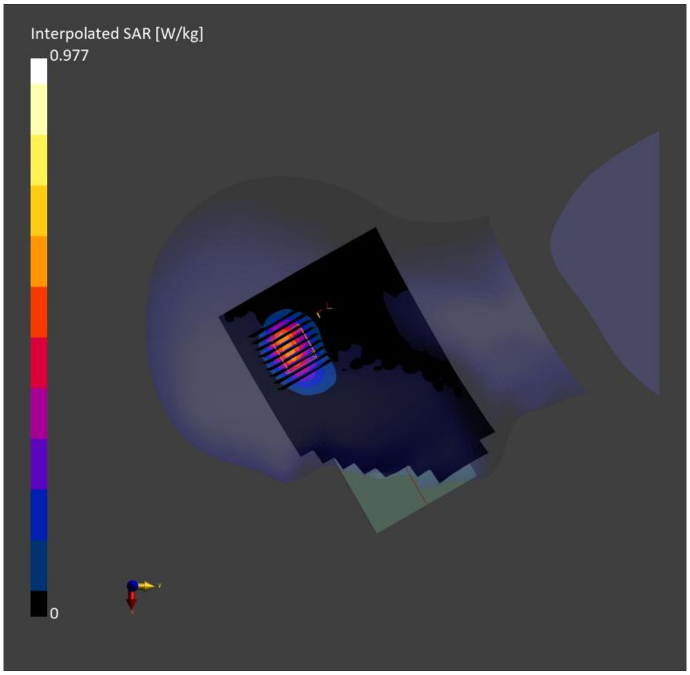
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-04	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-04	2025-06-04
psSAR1g [W/kg]	0.480	0.470
psSAR10g [W/kg]	0.248	0.243
Power Drift [dB]	-0.04	-0.07
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		76.0
Dist 3dB Peak [mm]		7.3



Measurement Report for Device, P9 LTE 12_QPSK10M_Right Cheek_Ch 23060_1RB_OS24

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, HSL	CHEEK, 0.00	Band 12	LTE-FDD, 10175-CAH	704.000, 23060	9.99	0.852	40.5

Hardware Setup

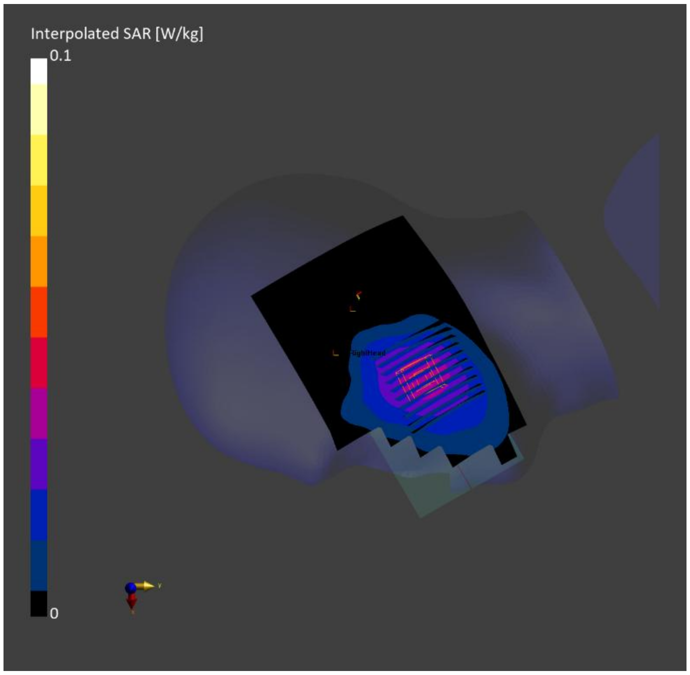
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-03	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-03	2025-06-03
psSAR1g [W/kg]	0.034	0.032
psSAR10g [W/kg]	0.024	0.027
Power Drift [dB]	0.05	-0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		87.7
Dist 3dB Peak [mm]		21.9



Measurement Report for Device, P10 LTE 41_QPSK20M_Right Cheek_Ch 39750_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, **HSL**	CHEEK, 0.00	Band 41	LTE-TDD, 10172-CAH	2506.000, 39750	7.64	1.83	39.8

Hardware Setup

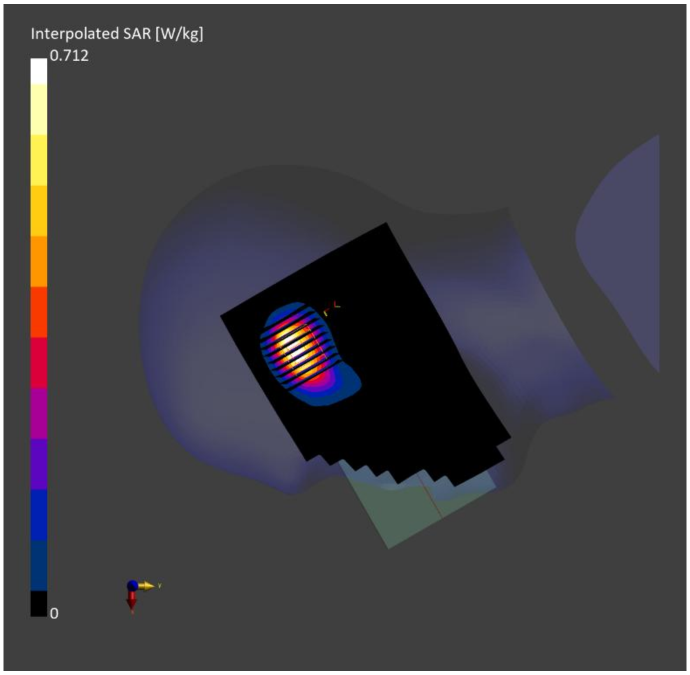
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-04	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-04	2025-06-04
psSAR1g [W/kg]	0.358	0.374
psSAR10g [W/kg]	0.184	0.193
Power Drift [dB]	0.08	-0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		83.6
Dist 3dB Peak [mm]		7.3



Measurement Report for Device, P11 N2_SCS15kHz_DFT-s-OFDM BPSK 20M_Left Cheek_Ch 376000_1RB_OS104

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, **HSL**	CHEEK, 0.00	Band n2	5G NR FR1 FDD, 10931-AAC	1880.000, 376000	7.77	1.39	39.7

Hardware Setup

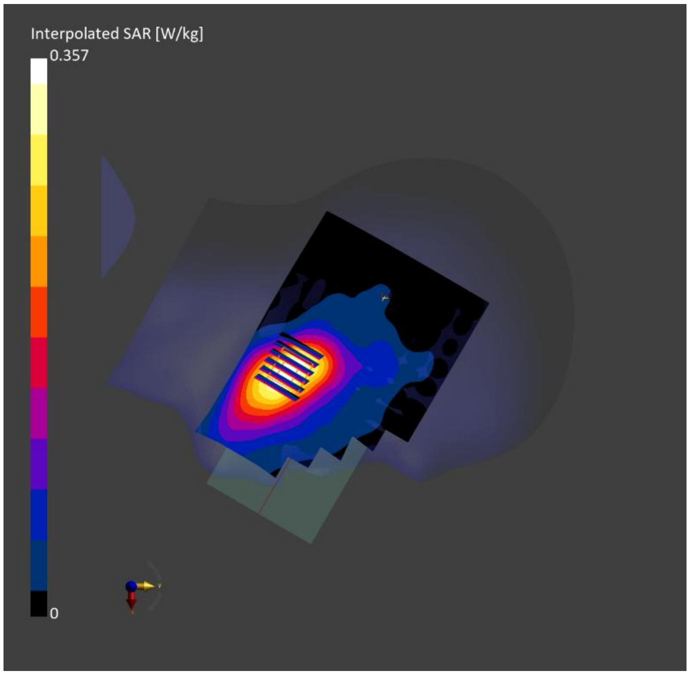
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-02	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-02	2025-06-02
psSAR1g [W/kg]	0.222	0.238
psSAR10g [W/kg]	0.132	0.157
Power Drift [dB]	0.06	0.05
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		87.1
Dist 3dB Peak [mm]		15.8



Measurement Report for Device, P12 N5_SCS15kHz_DFT-s-OFDM BPSK 20M_Right Cheek_Ch 166800_1RB_OS1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, **HSL**	CHEEK, 0.00	Band n5	5G NR FR1 FDD, 10931-AAC	834.000, 166800	9.70	0.890	40.4

Hardware Setup

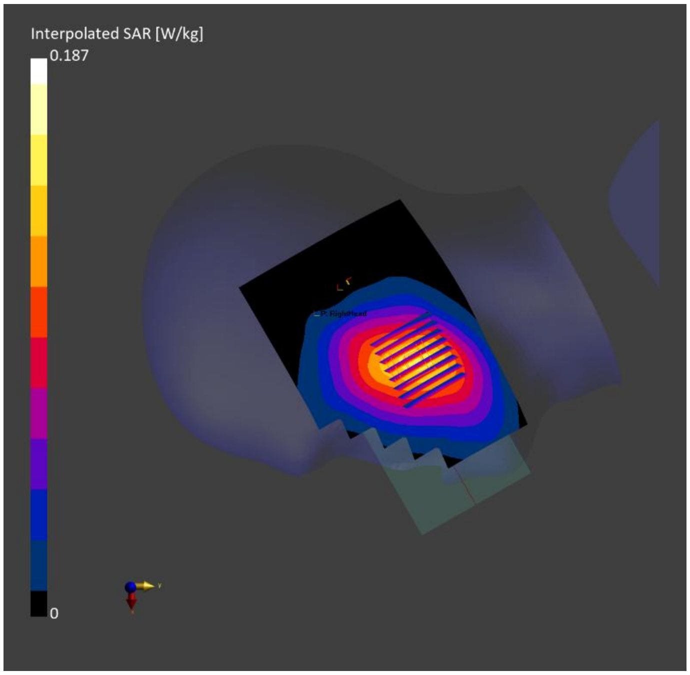
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-May-30	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-30	2025-05-30
psSAR1g [W/kg]	0.129	0.138
psSAR10g [W/kg]	0.089	0.109
Power Drift [dB]	-0.08	0.05
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		88.5
Dist 3dB Peak [mm]		24.5



Measurement Report for Device, P13 N7_SCS15kHz_DFT-s-OFDM BPSK 40M_Right Cheek_Ch 504000_1RB_OS214

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, HSL	CHEEK, 0.00	Band n7	5G NR FR1 FDD, 10942-AAC	2520.000, 504000	7.64	1.84	39.8

Hardware Setup

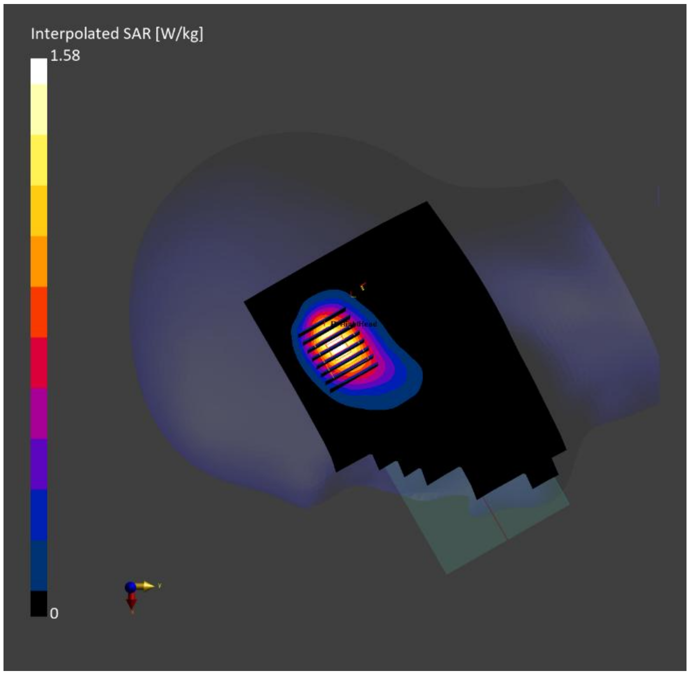
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-04	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-04	2025-06-04
psSAR1g [W/kg]	0.904	0.929
psSAR10g [W/kg]	0.462	0.490
Power Drift [dB]	-0.04	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		86.0
Dist 3dB Peak [mm]		12.2



Measurement Report for Device, P14 N26_SCS15kHz_DFT-s-OFDM BPSK 20M_Right Cheek_Ch 167300_1RB_OS1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, HSL	CHEEK, 0.00	Band n26	5G NR FR1 FDD, 10931-AAC	836.500, 167300	9.70	0.891	40.4

Hardware Setup

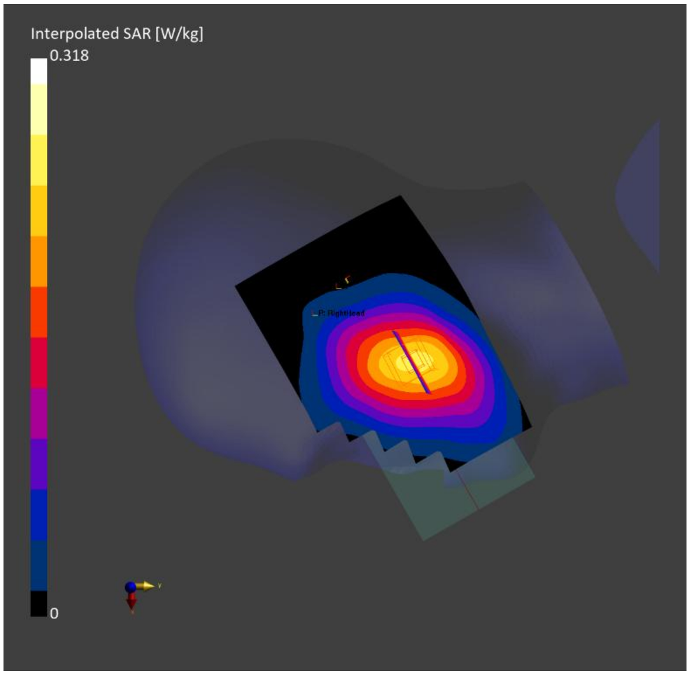
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-May-30	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-30	2025-05-30
psSAR1g [W/kg]	0.219	0.233
psSAR10g [W/kg]	0.151	0.183
Power Drift [dB]	-0.00	-0.07
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		88.3
Dist 3dB Peak [mm]		23.7



Measurement Report for Device, P15 N41_SCS30kHz_DFT-s-OFDM BPSK 100M_Right Cheek_Ch 509202_135RB_OS69

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, **HSL**	CHEEK, 0.00	Band n41	5G NR FR1 TDD, 10917-AAD	2546.010, 509202	7.64	1.86	39.7

Hardware Setup

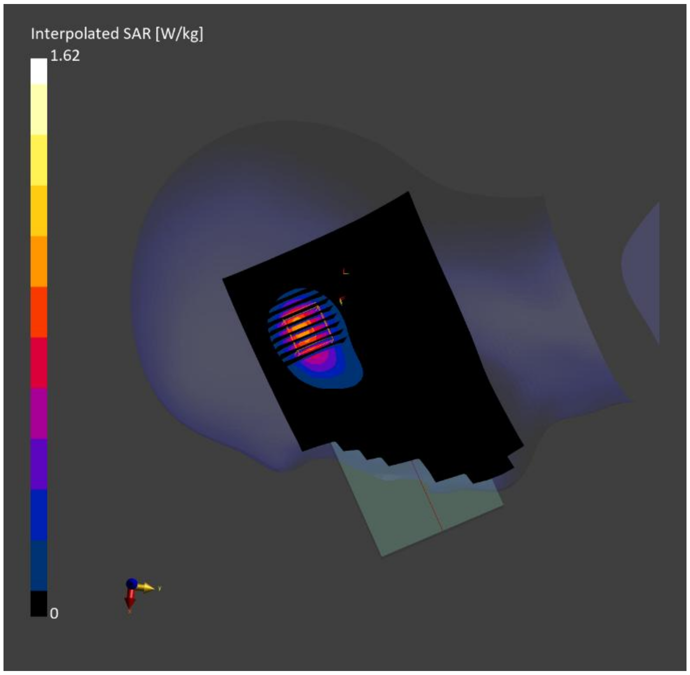
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-04	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-04	2025-06-04
psSAR1g [W/kg]	0.819	0.811
psSAR10g [W/kg]	0.410	0.424
Power Drift [dB]	-0.01	-0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		78.6
Dist 3dB Peak [mm]		7.9



Measurement Report for Device, P16 N66_SCS15kHz_DFT-s-OFDM BPSK 20M_Left Cheek_Ch 349000_1RB_OS104

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, **HSL**	CHEEK, 0.00	Band n66	5G NR FR1 FDD, 10931-AAC	1745.000, 349000	8.40	1.32	40.0

Hardware Setup

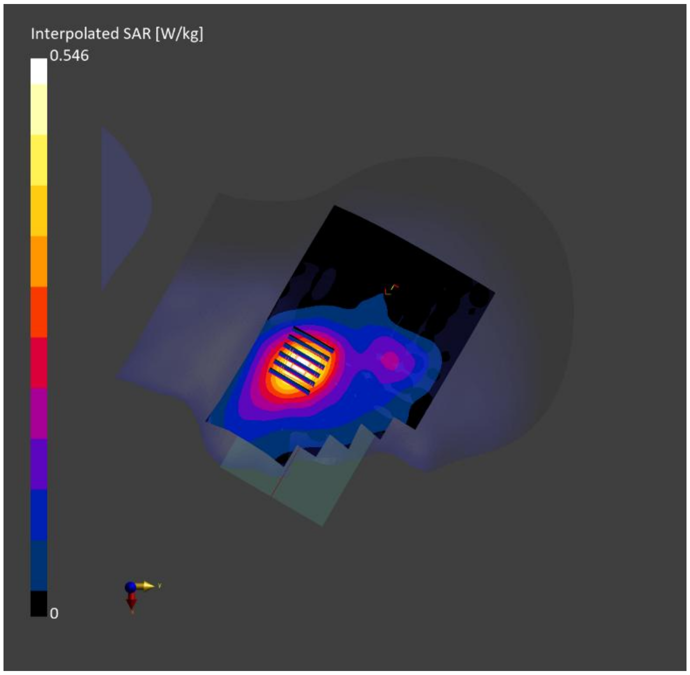
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-03	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-03	2025-06-03
psSAR1g [W/kg]	0.317	0.338
psSAR10g [W/kg]	0.186	0.211
Power Drift [dB]	-0.03	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		84.3
Dist 3dB Peak [mm]		13.9



Measurement Report for Device, P17 N77-1_SCS30kHz_DFT-s-OFDM BPSK 100M_Right Cheek_Ch 656667_135RB_OS69

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, **HSL**	CHEEK, 0.00	Band n77	5G NR FR1 TDD, 10917-AAD	3850.005, 656667	6.75	3.26	37.1

Hardware Setup

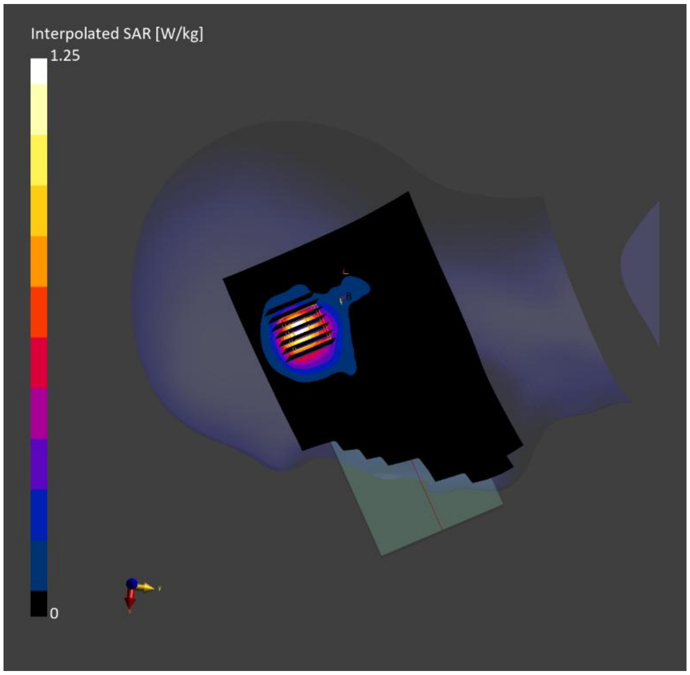
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-05	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	28.0 x 28.0 x 28.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-05	2025-06-05
psSAR1g [W/kg]	0.496	0.539
psSAR10g [W/kg]	0.210	0.228
Power Drift [dB]	-0.03	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		79.0
Dist 3dB Peak [mm]		7.9



Measurement Report for Device, P18 N77-2_SCS30kHz_DFT-s-OFDM BPSK 100M_Right Cheek_Ch 662000_135RB_OS69

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, **HSL**	CHEEK, 0.00	Band n77	5G NR FR1 TDD, 10917-AAD	3930.000, 662000	6.75	3.44	37.0

Hardware Setup

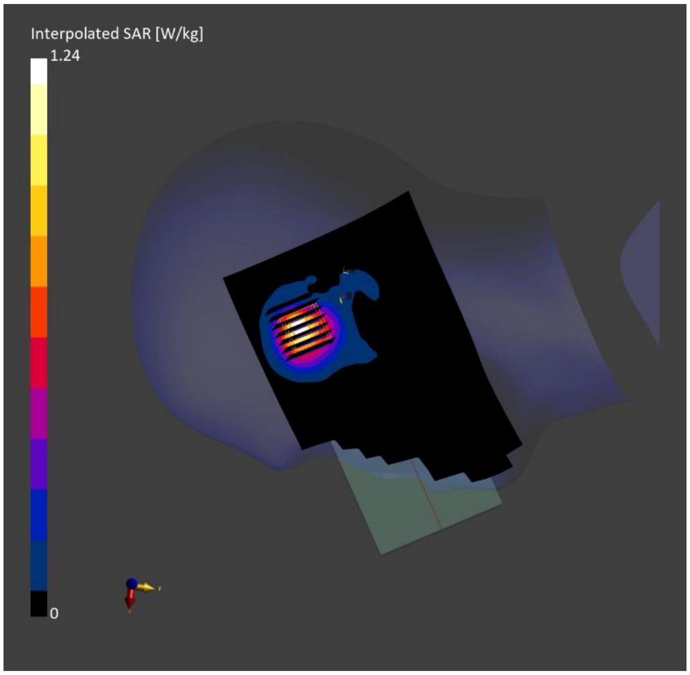
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-05	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	28.0 x 28.0 x 28.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-05	2025-06-05
psSAR1g [W/kg]	0.491	0.533
psSAR10g [W/kg]	0.204	0.229
Power Drift [dB]	0.06	0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		79.1
Dist 3dB Peak [mm]		7.7



Measurement Report for Device, P19 802.11b_Left Cheek_Ch 1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, **HSL**	CHEEK, 0.00	WLAN 2.4GHz	WLAN, 10012-CAB	2412.000, 1	7.6	1.76	39.9

Hardware Setup

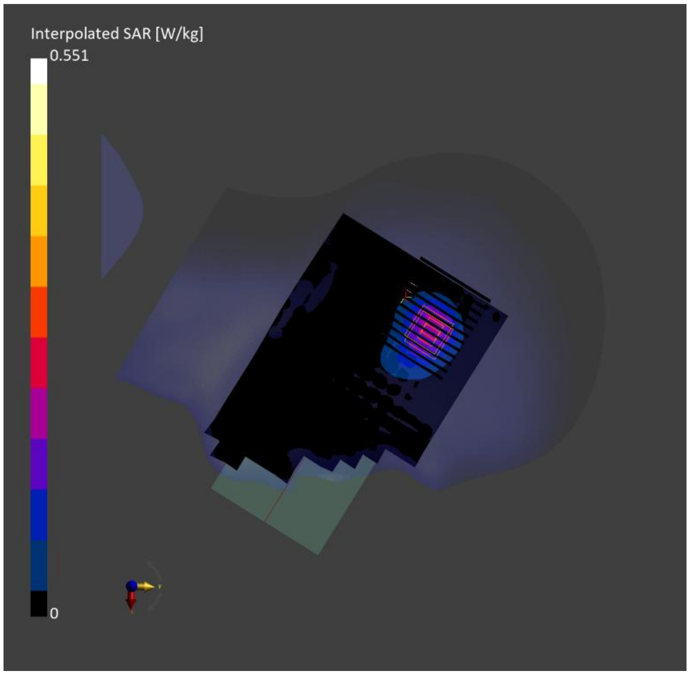
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-06	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-06	2025-06-06
psSAR1g [W/kg]	0.172	0.172
psSAR10g [W/kg]	0.094	0.095
Power Drift [dB]	0.01	0.05
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		78.7
Dist 3dB Peak [mm]		9.6



Measurement Report for Device, P20 802.11a_Left Tilted_Ch 48

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, **HSL**	TILT, 0.00	U-NII-1, U-NII-2A	WLAN, 10317-AAE	5240.000, 48	5.45	4.55	37.5

Hardware Setup

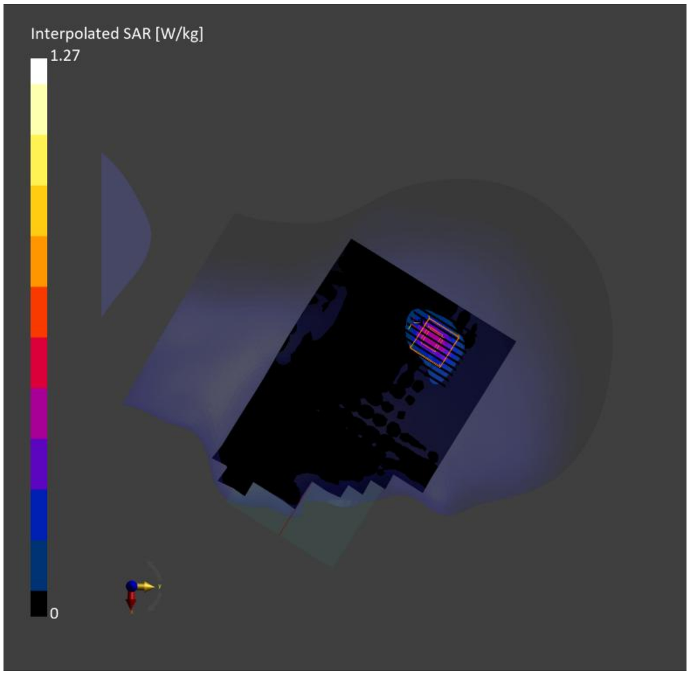
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-06	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-06	2025-06-06
psSAR1g [W/kg]	0.377	0.372
psSAR10g [W/kg]	0.142	0.129
Power Drift [dB]	0.01	0.13
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		66.4
Dist 3dB Peak [mm]		7.7



Measurement Report for Device, P21 802.11a_Left Tilted_Ch 149

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, HSL	TILT, 0.00	U-NII-2C, U-NII-3	WLAN, 10317-AAE	5745.000, 149	4.98	5.10	36.6

Hardware Setup

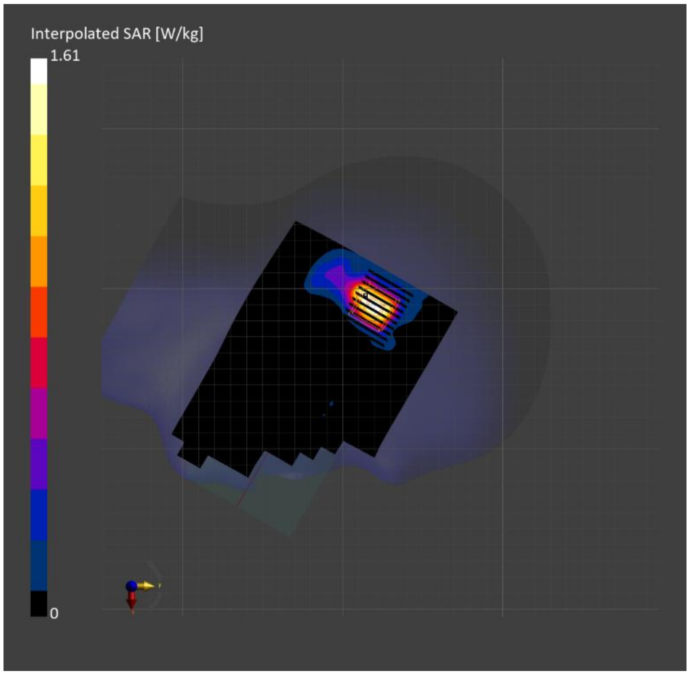
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-06	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	N/A
Surface Detection	VMS + 6p	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-06	2025-06-06
psSAR1g [W/kg]	0.369	0.406
psSAR10g [W/kg]	0.137	0.128
Power Drift [dB]	-0.17	0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		60.9
Dist 3dB Peak [mm]		8.1



Measurement Report for Device, P22 BT_3DH5_Left Cheek_Ch 78

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, **HSL**	CHEEK, 0.00	Custom Band	CW, 10038-CAA	2480.000, 2480000	7.6	1.81	39.9

Hardware Setup

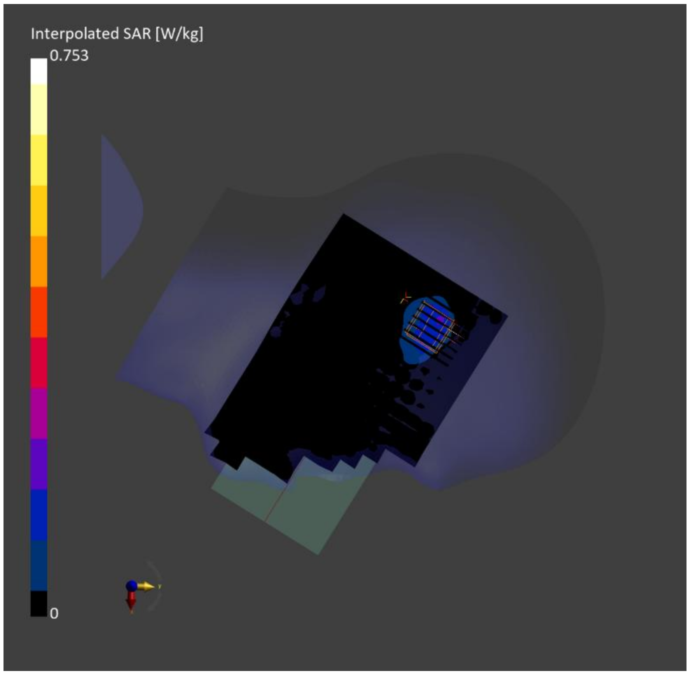
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-06	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	4.9 x 4.9 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-06	2025-06-06
psSAR1g [W/kg]	0.019	0.016
psSAR10g [W/kg]	0.01	0.008
Power Drift [dB]	0.58	-0.35
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		69.8
Dist 3dB Peak [mm]		7.6



Measurement Report for Device, P23 GSM850_GPRS 2TS_Rear Face_1cm_Ch 251

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 10.00	GSM 850	GSM, 10024-DAC	848.800, 251	9.70	0.895	40.3

Hardware Setup

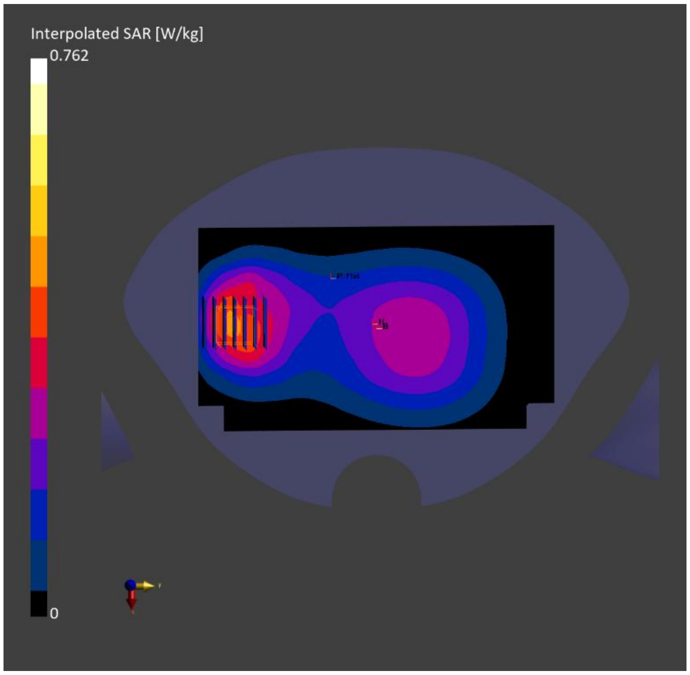
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-May-29	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-29	2025-05-29
psSAR1g [W/kg]	0.405	0.417
psSAR10g [W/kg]	0.271	0.258
Power Drift [dB]	-0.04	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		81.0
Dist 3dB Peak [mm]		14.1



Measurement Report for Device, P24 GSM1900_GPRS 2TS_Rear Face_1cm_Ch 512

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 10.00	PCS 1900	GSM, 10024-DAC	1850.200, 512	7.77	1.38	39.8

Hardware Setup

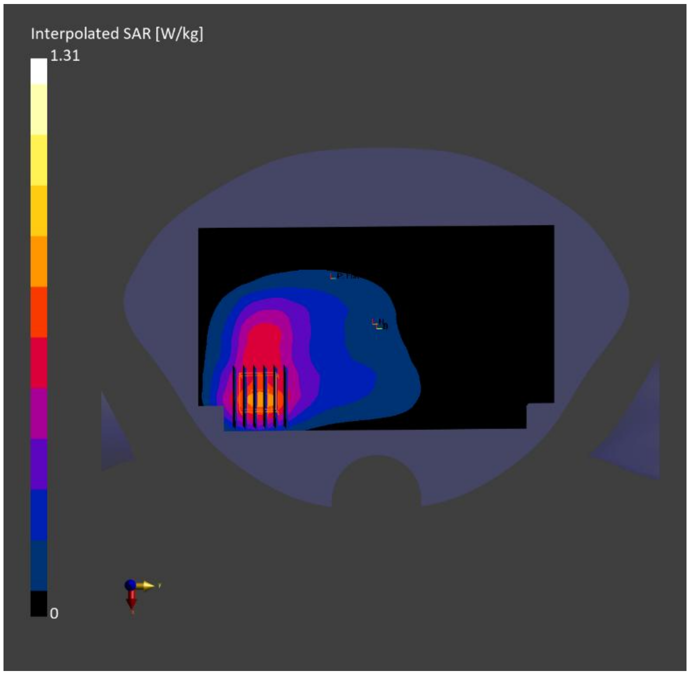
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-02	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-02	2025-06-02
psSAR1g [W/kg]	0.675	0.671
psSAR10g [W/kg]	0.401	0.382
Power Drift [dB]	-0.02	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		80.3
Dist 3dB Peak [mm]		11.9



Measurement Report for Device, P25 WCDMA II_RMC12.2K_Rear Face_1cm_Ch 9400

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 10.00	Band 2	WCDMA, 10011-CAC	1880.000, 9400	7.77	1.39	39.7

Hardware Setup

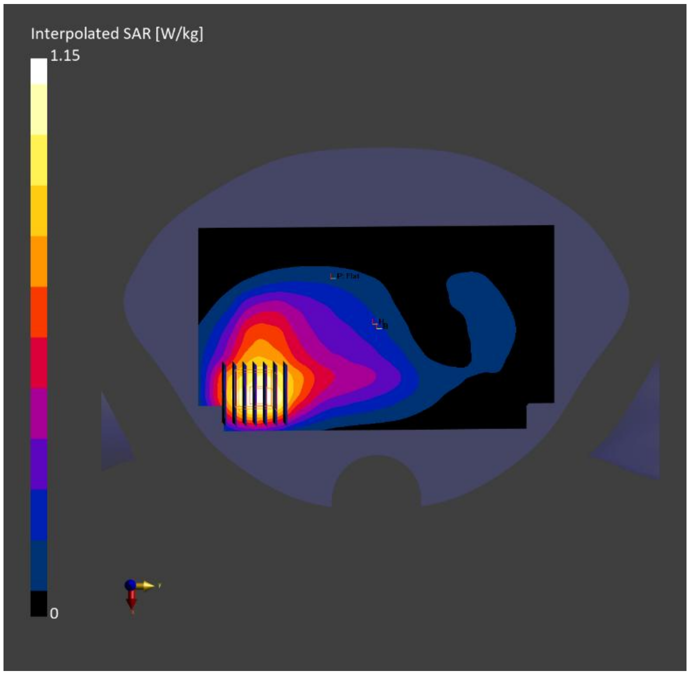
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-02	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-02	2025-06-02
psSAR1g [W/kg]	0.584	0.586
psSAR10g [W/kg]	0.351	0.345
Power Drift [dB]	0.01	-0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		78.7
Dist 3dB Peak [mm]		12.4



Measurement Report for Device, P26 WCDMA V_RMC12.2K_Rear Face_1cm_Ch 4233

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 10.00	Band 5	WCDMA, 10011-CAC	846.600, 4233	9.70	0.894	40.3

Hardware Setup

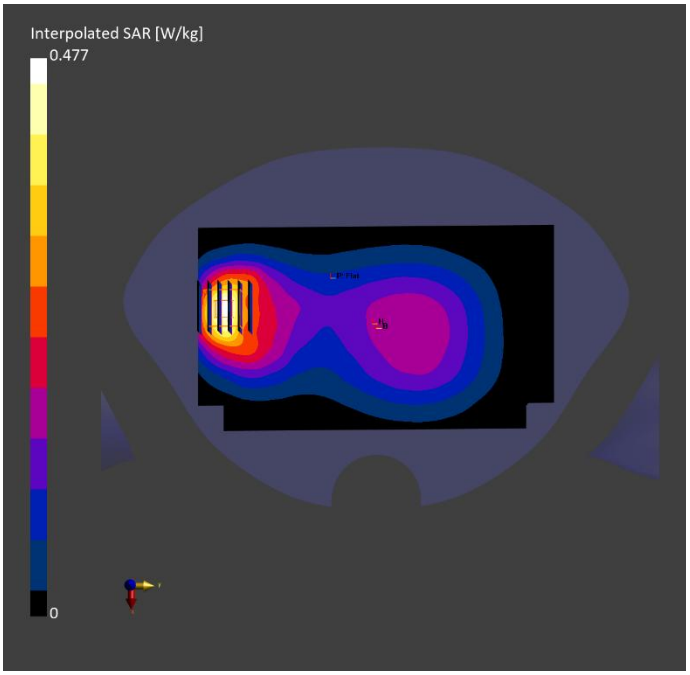
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-May-29	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-29	2025-05-29
psSAR1g [W/kg]	0.239	0.244
psSAR10g [W/kg]	0.151	0.141
Power Drift [dB]	-0.00	-0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		76.5
Dist 3dB Peak [mm]		12.3



Measurement Report for Device, P27 LTE2_QPSK20M_Rear Face_1cm_Ch 18700_1RB_OS99

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 10.00	Band 2	LTE-FDD, 10169-CAF	1860.000, 18700	7.77	1.39	39.8

Hardware Setup

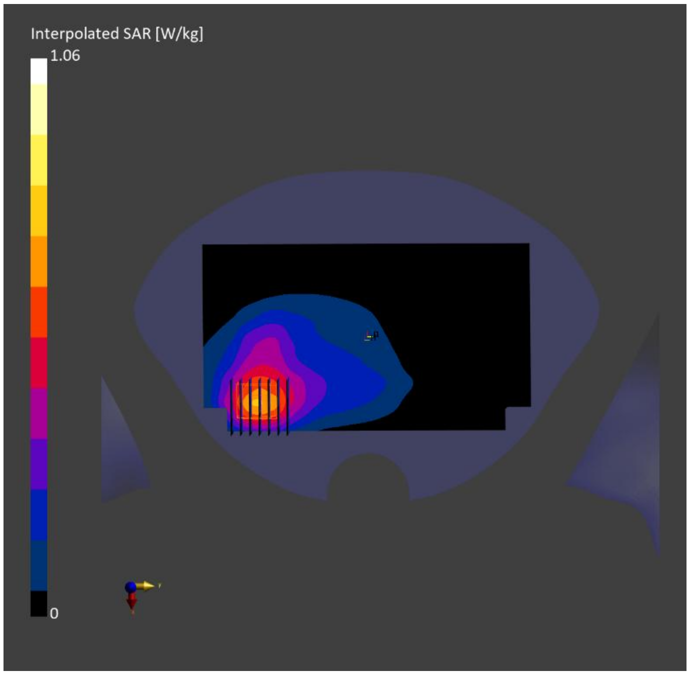
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-02	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-02	2025-06-02
psSAR1g [W/kg]	0.596	0.548
psSAR10g [W/kg]	0.355	0.335
Power Drift [dB]	-0.25	0.16
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		79.0
Dist 3dB Peak [mm]		11.4



Measurement Report for Device, P28 LTE66_QPSK20M_Rear Face_1cm_Ch 132572_1RB_OS99

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	FRONT, 10.00	Band 66	LTE-FDD, 10169-CAF	1770.000, 132572	8.40	1.34	40.0

Hardware Setup

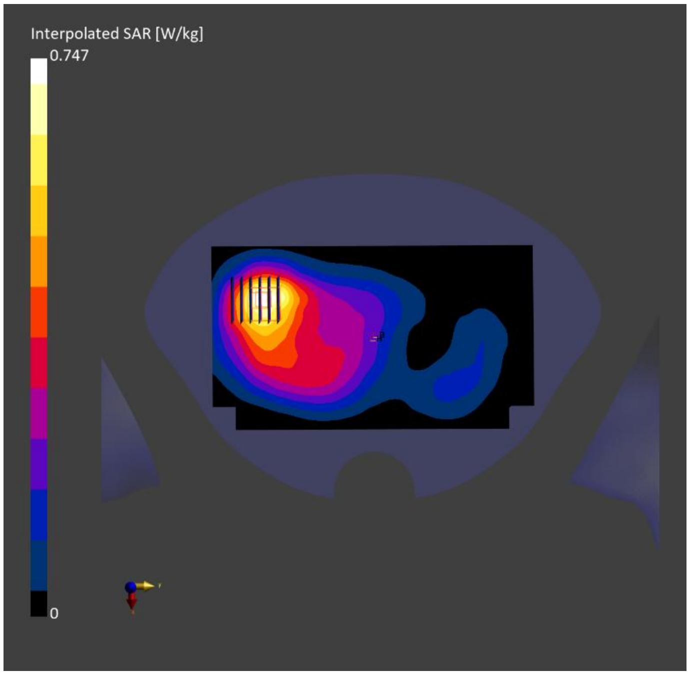
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-03	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-03	2025-06-03
psSAR1g [W/kg]	0.413	0.417
psSAR10g [W/kg]	0.246	0.257
Power Drift [dB]	0.06	-0.11
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		79.5
Dist 3dB Peak [mm]		13.5



Measurement Report for Device, P29 LTE5_QPSK10M_Rear Face_1cm_Ch 20525_1RB_OS24

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 10.00	Band 5	LTE-FDD, 10175-CAH	836.500, 20525	9.70	0.891	40.4

Hardware Setup

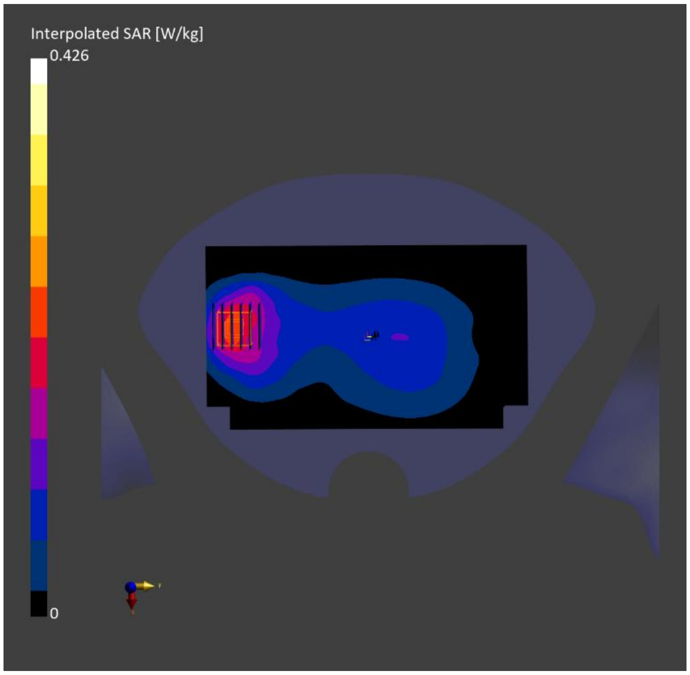
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-May-29	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-29	2025-05-29
psSAR1g [W/kg]	0.205	0.221
psSAR10g [W/kg]	0.134	0.129
Power Drift [dB]	-0.02	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		79.9
Dist 3dB Peak [mm]		13.2



Measurement Report for Device, P30 LTE7_QPSK20M_Rear Face_1cm_Ch 21100_1RB_OS99

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 10.00	Band 7	LTE-FDD, 10169-CAF	2535.000, 21100	7.64	1.85	39.8

Hardware Setup

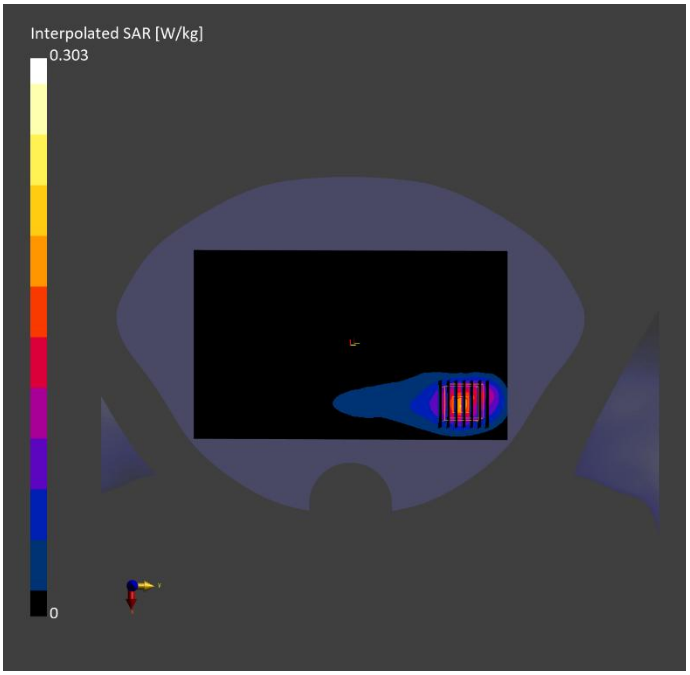
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-04	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-04	2025-06-04
psSAR1g [W/kg]	0.151	0.148
psSAR10g [W/kg]	0.072	0.069
Power Drift [dB]	-0.05	0.05
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		80.7
Dist 3dB Peak [mm]		10.2



Measurement Report for Device, P31 LTE12_QPSK10M_Rear Face_1cm_Ch 23060_1RB_OS24

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 10.00	Band 12	LTE-FDD, 10175-CAH	704.000, 23060	9.99	0.852	40.5

Hardware Setup

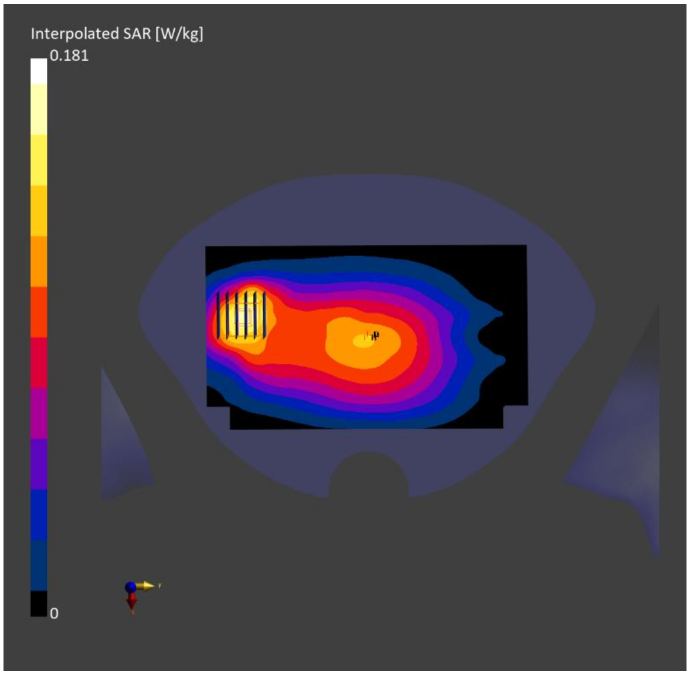
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-03	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-03	2025-06-03
psSAR1g [W/kg]	0.078	0.084
psSAR10g [W/kg]	0.053	0.049
Power Drift [dB]	-0.03	0.05
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		73.6
Dist 3dB Peak [mm]		13.0



Measurement Report for Device, P32 LTE41_QPSK20M_Rear Face_1cm_Ch 39750_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 10.00	Band 41	LTE-TDD, 10172-CAH	2506.000, 39750	7.64	1.83	39.8

Hardware Setup

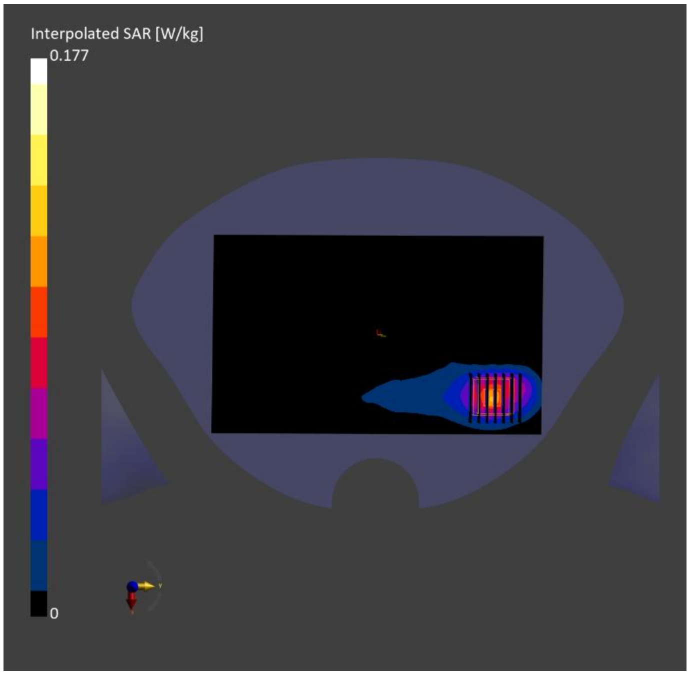
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-04	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-04	2025-06-04
psSAR1g [W/kg]	0.090	0.089
psSAR10g [W/kg]	0.043	0.041
Power Drift [dB]	0.12	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		81.7
Dist 3dB Peak [mm]		10.3



Measurement Report for Device, P33 N2_SCS15kHz_DFT-s-OFDM BPSK 20M_Rear Face_1cm_Ch 376000_1RB_OS104

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 10.00	Band n2	5G NR FR1 FDD, 10931-AAC	1880.000, 376000	7.77	1.39	39.7

Hardware Setup

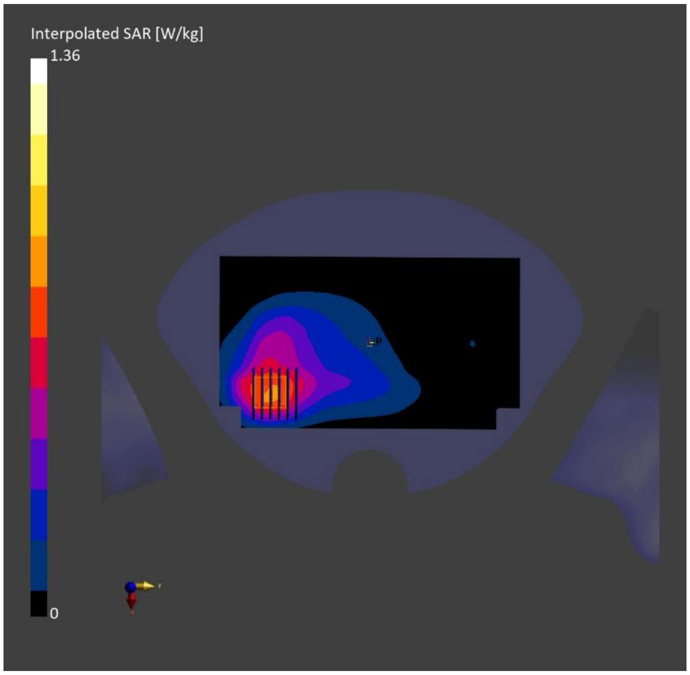
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-02	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-02	2025-06-02
psSAR1g [W/kg]	0.696	0.707
psSAR10g [W/kg]	0.426	0.417
Power Drift [dB]	-0.05	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		79.6
Dist 3dB Peak [mm]		12.1



Measurement Report for Device, P34 N5_SCS15kHz_DFT-s-OFDM BPSK 20M_Rear Face_1cm_Ch 166800_1RB_OS1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 10.00	Band n5	5G NR FR1 FDD, 10931-AAC	834.000, 166800	9.70	0.890	40.4

Hardware Setup

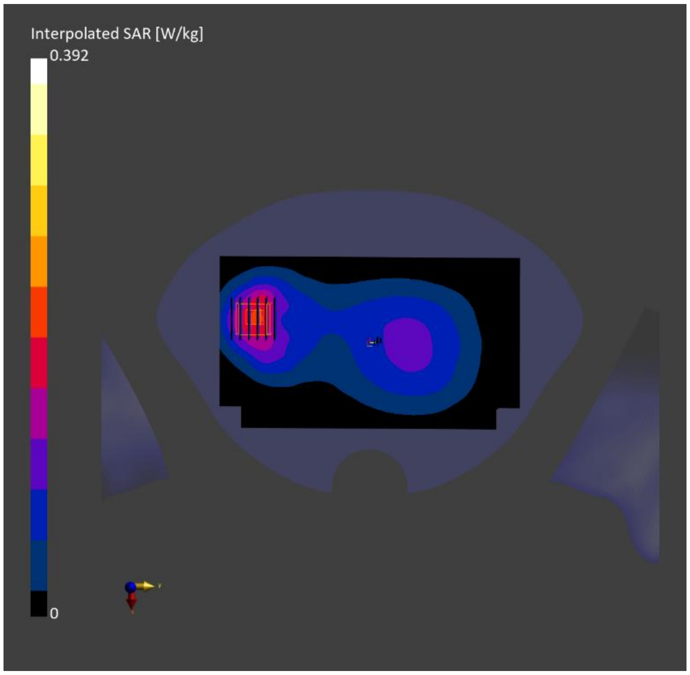
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-May-30	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-30	2025-05-30
psSAR1g [W/kg]	0.177	0.197
psSAR10g [W/kg]	0.117	0.112
Power Drift [dB]	0.12	0.09
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		76.2
Dist 3dB Peak [mm]		12.3



Measurement Report for Device, P35 N7_SCS15kHz_DFT-s-OFDM BPSK 40M_Rear Face_1cm_Ch 507000_1RB_OS214

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 10.00	Band n7	5G NR FR1 FDD, 10934-AAC	2535.000, 507000	7.64	1.85	39.8

Hardware Setup

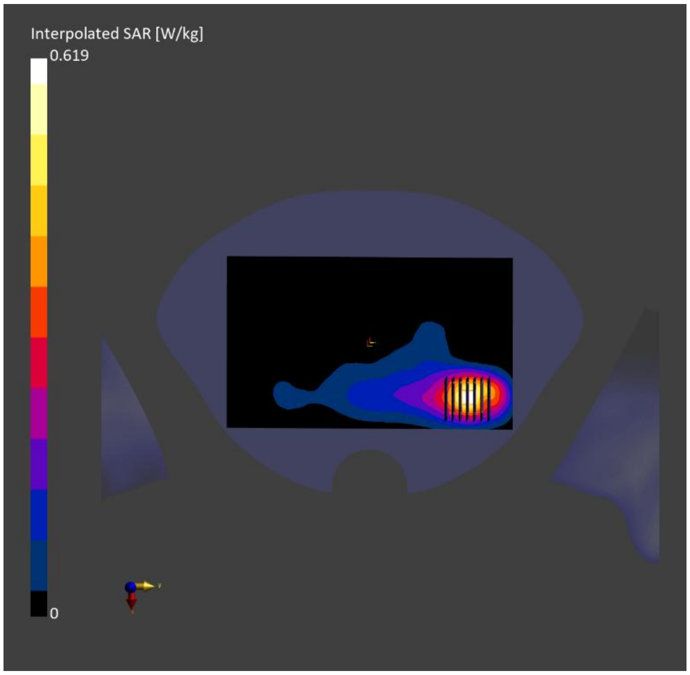
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-04	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-04	2025-06-04
psSAR1g [W/kg]	0.325	0.330
psSAR10g [W/kg]	0.162	0.166
Power Drift [dB]	-0.16	0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		82.9
Dist 3dB Peak [mm]		12.7



Measurement Report for Device, P36 N26_SCS15kHz_DFT-s-OFDM BPSK 20M_Rear Face_1cm_Ch 167300_1RB_OS1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 10.00	Band n26	5G NR FR1 FDD, 10931-AAC	836.500, 167300	9.70	0.891	40.4

Hardware Setup

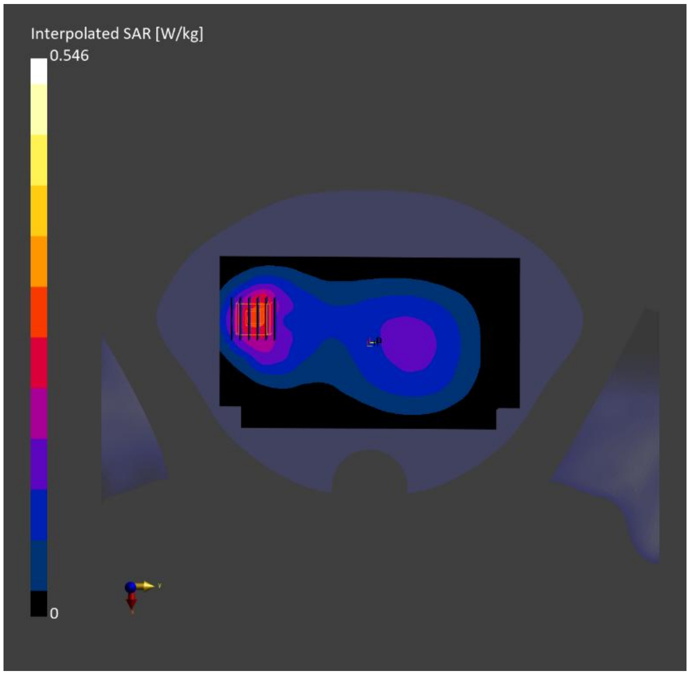
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-May-30	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-30	2025-05-30
psSAR1g [W/kg]	0.254	0.274
psSAR10g [W/kg]	0.168	0.157
Power Drift [dB]	-0.11	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		76.3
Dist 3dB Peak [mm]		13.3



Measurement Report for Device, P37 N41_SCS30kHz_DFT-s-OFDM BPSK 100M_Rear Face_1cm_Ch 518598_135RB_OS138

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 10.00	Band n41	5G NR FR1 TDD, 10917-AAD	2592.990, 518598	7.64	1.89	39.7

Hardware Setup

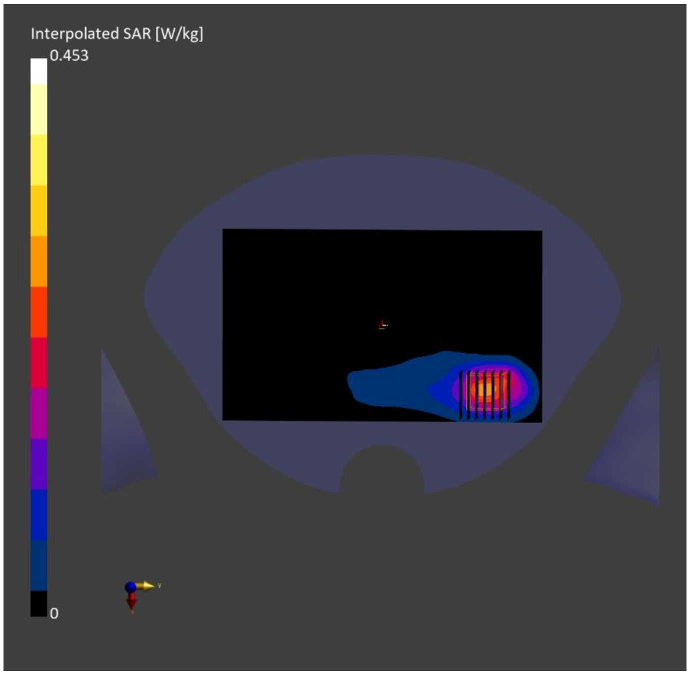
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-04	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-04	2025-06-04
psSAR1g [W/kg]	0.225	0.228
psSAR10g [W/kg]	0.115	0.110
Power Drift [dB]	0.13	0.29
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		81.4
Dist 3dB Peak [mm]		12.1



Measurement Report for Device, P38 N66_SCS15kHz_DFT-s-OFDM BPSK 20M_Rear Face_1cm_Ch 349000_1RB_OS104

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 10.00	Band n66	5G NR FR1 FDD, 10931-AAC	1745.000, 349000	8.40	1.32	40.0

Hardware Setup

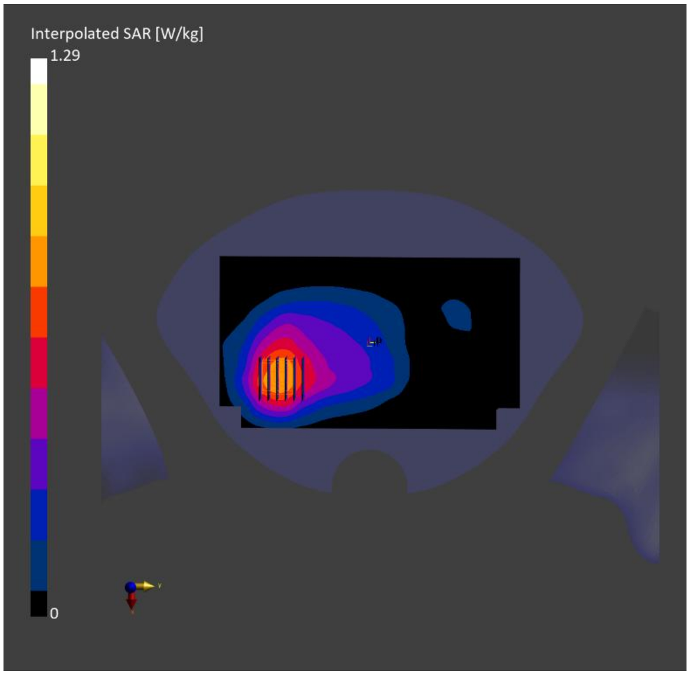
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-03	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-03	2025-06-03
psSAR1g [W/kg]	0.728	0.735
psSAR10g [W/kg]	0.450	0.452
Power Drift [dB]	-0.04	-0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		82.4
Dist 3dB Peak [mm]		> 15.0



Measurement Report for Device, P39 N77_SCS30kHz_DFT-s-OFDM BPSK 100M_Rear Face_1cm_Ch 656667_135RB_OS69

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 10.00	Band n77	5G NR FR1 TDD, 10917-AAD	3850.005, 656667	6.75	3.26	37.1

Hardware Setup

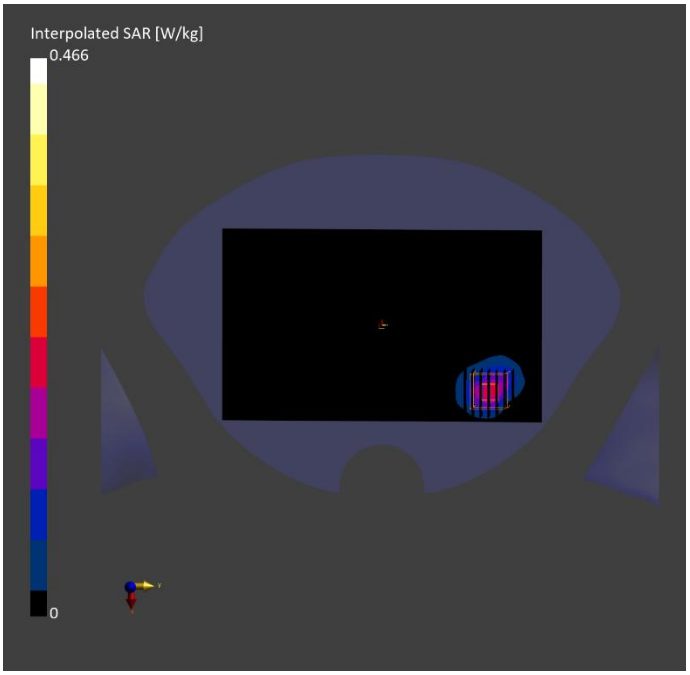
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-05	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	28.0 x 28.0 x 28.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-05	2025-06-05
psSAR1g [W/kg]	0.160	0.171
psSAR10g [W/kg]	0.063	0.064
Power Drift [dB]	0.73	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		74.0
Dist 3dB Peak [mm]		8.5



Measurement Report for Device, P40 N77_SCS30kHz_DFT-s-OFDM BPSK 100M_Rear Face_1cm_Ch 662000_135RB_OS69

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 10.00	Band n77	5G NR FR1 TDD, 10917-AAD	3930.000, 662000	6.75	3.44	37.0

Hardware Setup

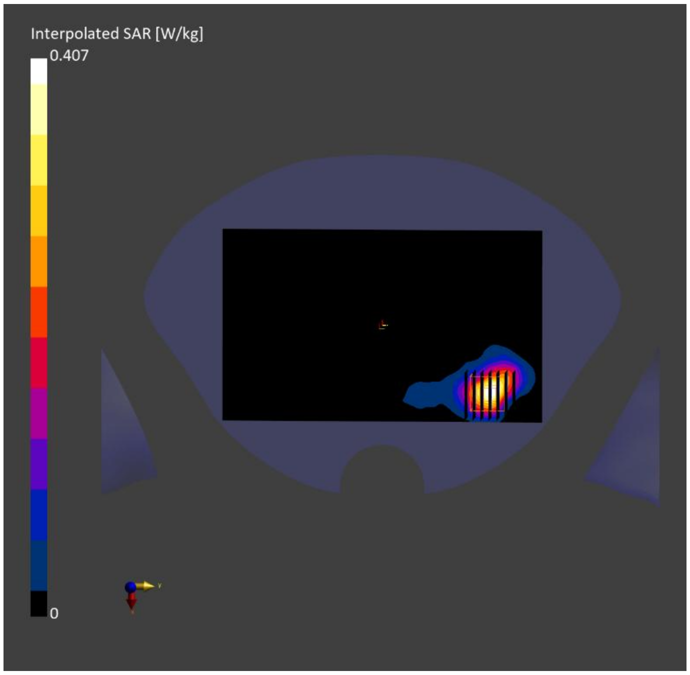
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-05	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	28.0 x 28.0 x 28.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-05	2025-06-05
psSAR1g [W/kg]	0.138	0.146
psSAR10g [W/kg]	0.055	0.054
Power Drift [dB]	0.07	0.06
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		72.9
Dist 3dB Peak [mm]		7.9



Measurement Report for Device, P41 802.11b_Rear Face_1cm_Ch1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 10.00	WLAN 2.4GHz	WLAN, 10012-CAB	2412.000, 1	7.6	1.76	39.9

Hardware Setup

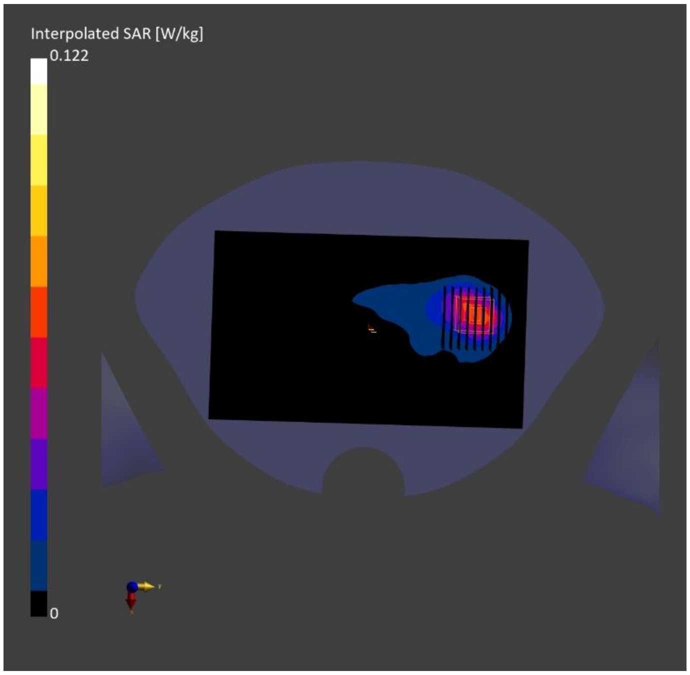
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-06	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-06	2025-06-06
psSAR1g [W/kg]	0.054	0.055
psSAR10g [W/kg]	0.028	0.027
Power Drift [dB]	-0.04	0.07
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		75.1
Dist 3dB Peak [mm]		10.9



Measurement Report for Device, P42 802.11a_Rear Face_1cm_Ch 48

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 10.00	U-NII-1, U-NII-2A	WLAN, 10317-AAE	5240.000, 48	5.45	4.55	37.5

Hardware Setup

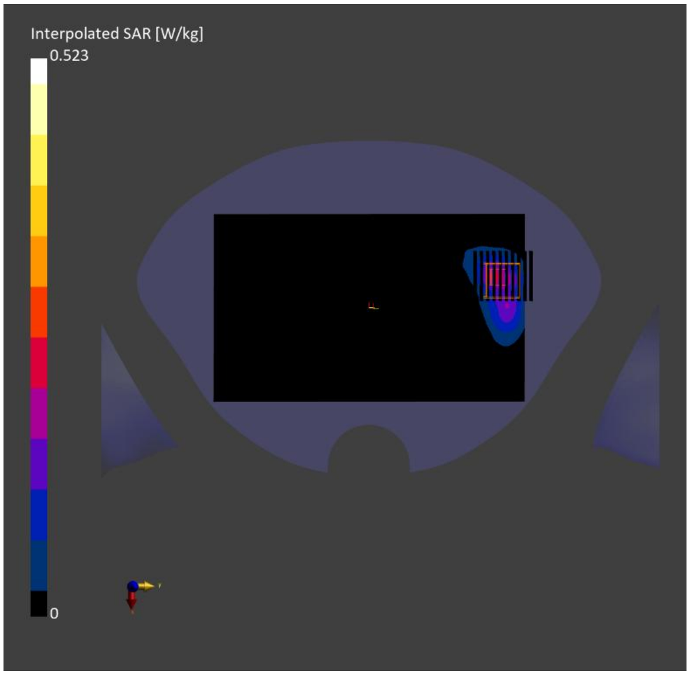
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-06	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-06	2025-06-06
psSAR1g [W/kg]	0.172	0.171
psSAR10g [W/kg]	0.064	0.059
Power Drift [dB]	-0.31	0.57
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		69.9
Dist 3dB Peak [mm]		10.2



Measurement Report for Device, P43 802.11a_Front Face_1cm_Ch 149

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	FRONT, 10.00	U-NII-2C, U-NII-3	WLAN, 10317-AAE	5745.000, 149	4.98	5.10	36.6

Hardware Setup

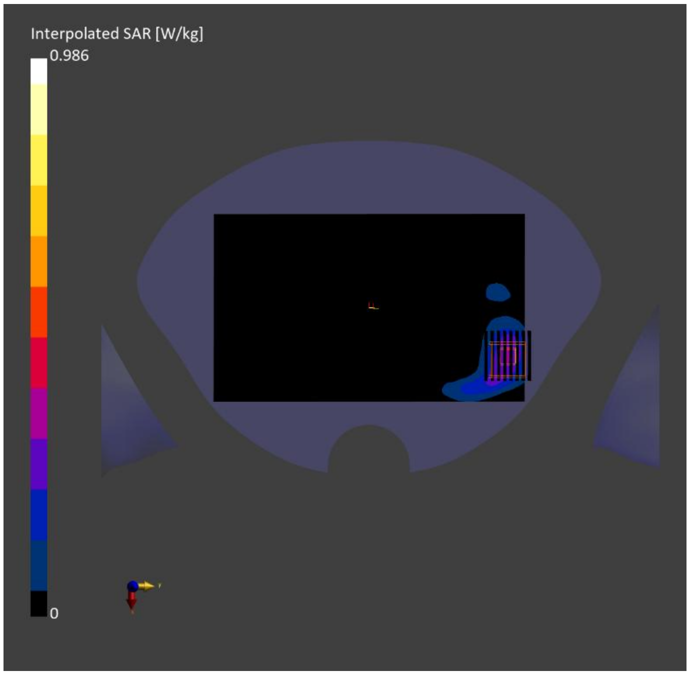
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-06	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-06	2025-06-06
psSAR1g [W/kg]	0.257	0.267
psSAR10g [W/kg]	0.106	0.100
Power Drift [dB]	-0.02	0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		61.3
Dist 3dB Peak [mm]		12.2



Measurement Report for Device, P44 BT_3DH5_Front Face_1cm_Ch 78

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	FRONT, 10.00	Custom Band	CW, 10038-CAA	2480.000, 2480000	7.6	1.81	39.9

Hardware Setup

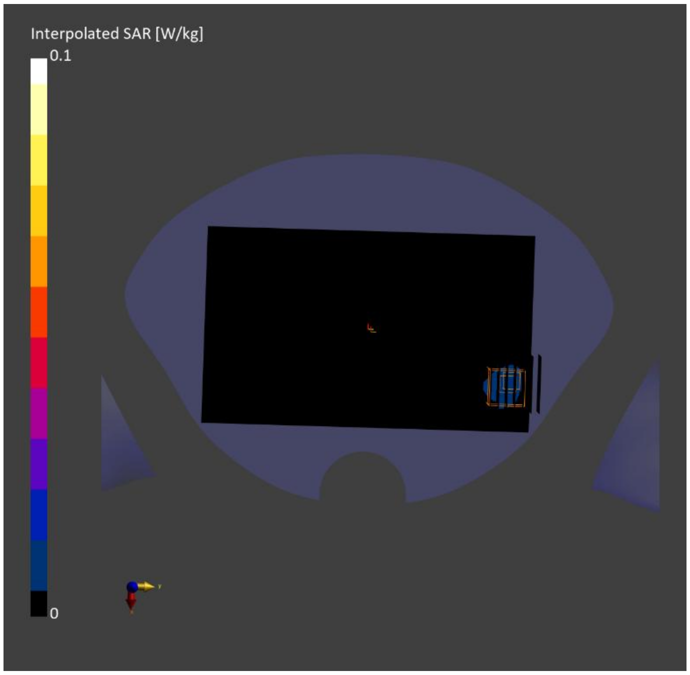
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-06	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-06	2025-06-06
psSAR1g [W/kg]	0.012	0.011
psSAR10g [W/kg]	0.006	0.005
Power Drift [dB]	0.08	0.05
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		66.8
Dist 3dB Peak [mm]		6.8



Measurement Report for Device, P45 GSM850_GPRS 2TS_Rear Face_1cm_Ch 251

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, **HSL**	BACK, 10.00	GSM 850	GSM, 10024-DAC	848.800, 251	9.70	0.895	40.3

Hardware Setup

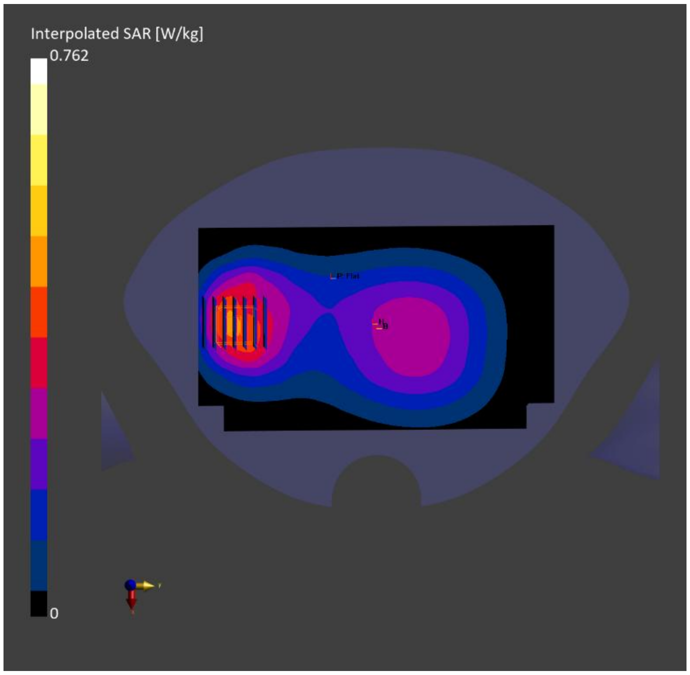
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-May-29	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-29	2025-05-29
psSAR1g [W/kg]	0.405	0.417
psSAR10g [W/kg]	0.271	0.258
Power Drift [dB]	-0.04	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		81.0
Dist 3dB Peak [mm]		14.1



Measurement Report for Device, P46 GSM1900_GPRS 2TS_Rear Face_1cm_Ch 512

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 10.00	PCS 1900	GSM, 10024-DAC	1850.200, 512	7.77	1.38	39.8

Hardware Setup

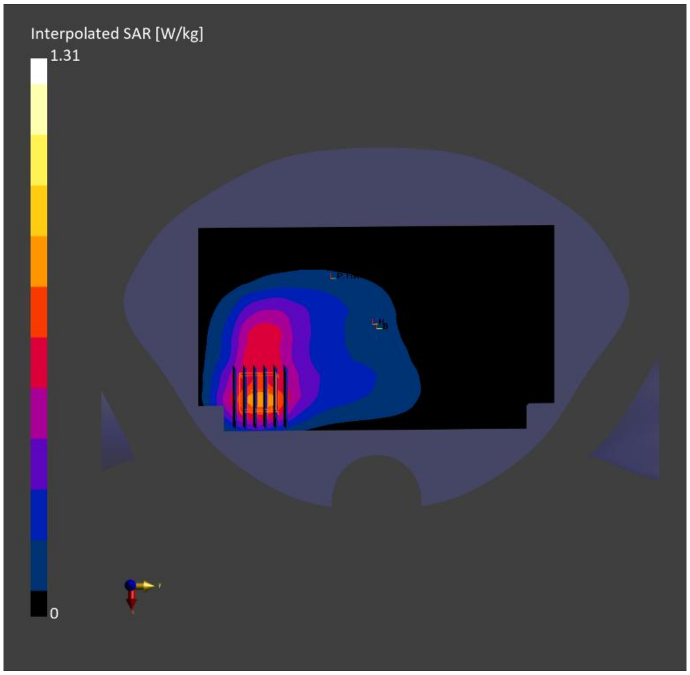
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-02	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-02	2025-06-02
psSAR1g [W/kg]	0.675	0.671
psSAR10g [W/kg]	0.401	0.382
Power Drift [dB]	-0.02	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		80.3
Dist 3dB Peak [mm]		11.9



Measurement Report for Device, P47 WCDMA II_RMC12.2K_Bottom Side_1cm_Ch 9400

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	EDGE BOTTOM, 10.00	Band 2	WCDMA, 10011-CAC	1880.000, 9400	7.77	1.39	39.7

Hardware Setup

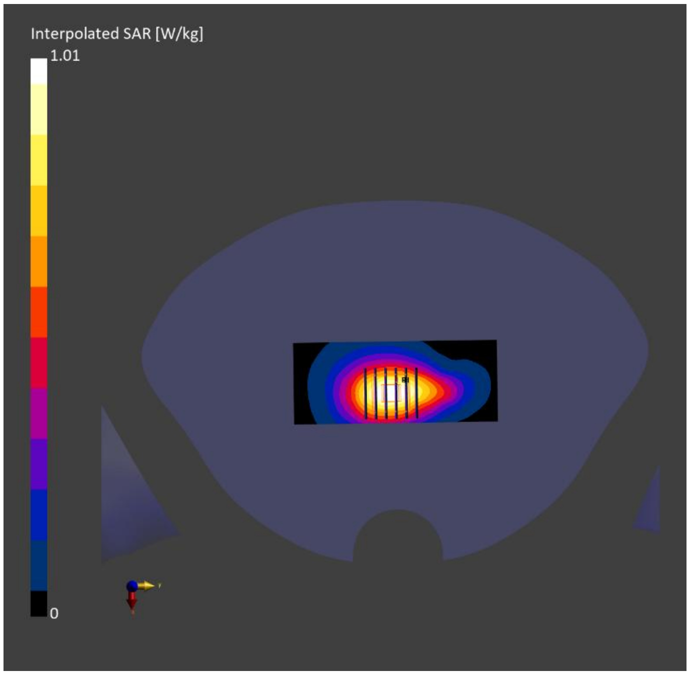
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-02	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	8.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-02	2025-06-02
psSAR1g [W/kg]	0.572	0.590
psSAR10g [W/kg]	0.329	0.350
Power Drift [dB]	0.00	0.01
Power Scaling	Enabled	Enabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		84.1
Dist 3dB Peak [mm]		14.5



Measurement Report for Device, P48 WCDMA V_RMC12.2K_Bottom Side_1cm_Ch 4233

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	EDGE BOTTOM, 10.00	Band 5	WCDMA, 10011-CAC	846.600, 4233	9.70	0.894	40.3

Hardware Setup

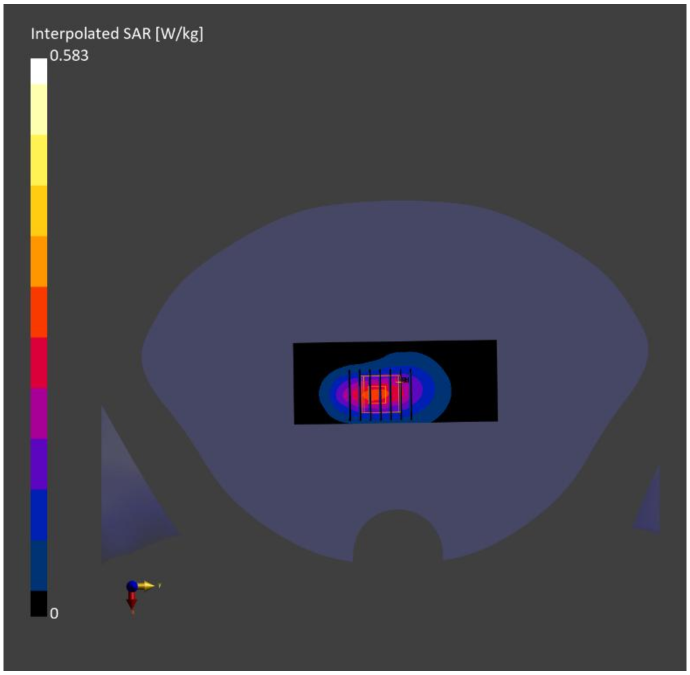
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-May-29	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	8.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-29	2025-05-29
psSAR1g [W/kg]	0.262	0.260
psSAR10g [W/kg]	0.154	0.137
Power Drift [dB]	-0.02	0.01
Power Scaling	Enabled	Enabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		74.1
Dist 3dB Peak [mm]		9.6



Measurement Report for Device, P49 LTE2_QPSK20M_Rear Face_1cm_Ch 18700_1RB_OS99

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 10.00	Band 2	LTE-FDD, 10169-CAF	1860.000, 18700	7.77	1.39	39.8

Hardware Setup

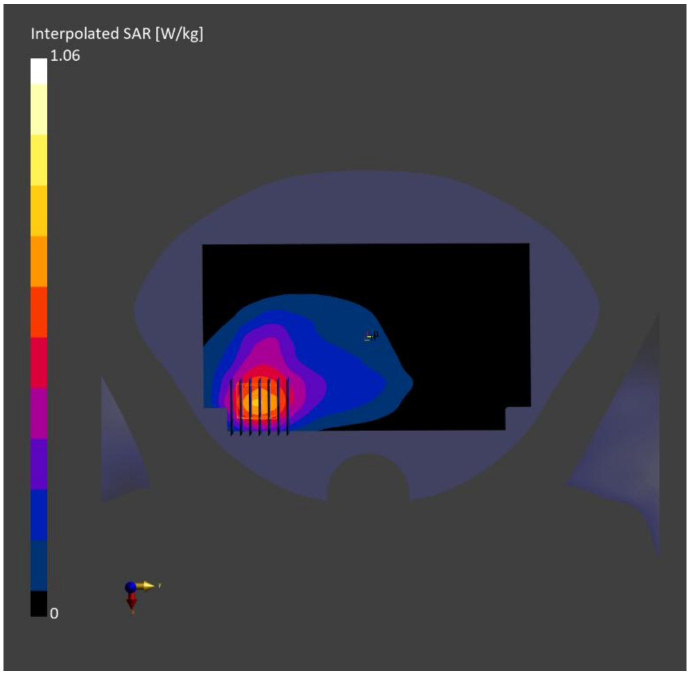
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-02	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-02	2025-06-02
psSAR1g [W/kg]	0.596	0.548
psSAR10g [W/kg]	0.355	0.335
Power Drift [dB]	-0.25	0.16
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		79.0
Dist 3dB Peak [mm]		11.4



Measurement Report for Device, P50 LTE66_QPSK20M_Bottom Side_1cm_Ch 132572_1RB_OS99

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	EDGE BOTTOM, 10.00	Band 66	LTE-FDD, 10169-CAF	1770.000, 132572	8.40	1.34	40.0

Hardware Setup

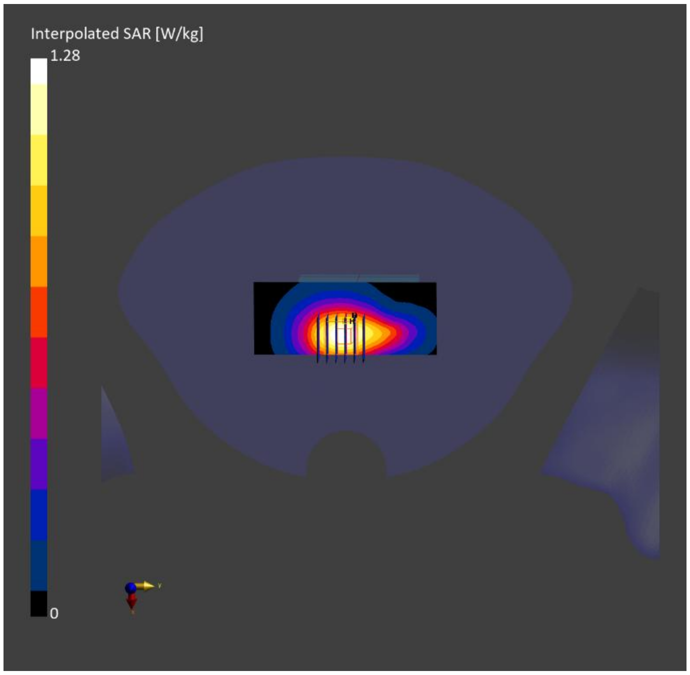
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-03	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	8.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-03	2025-06-03
psSAR1g [W/kg]	0.737	0.766
psSAR10g [W/kg]	0.431	0.466
Power Drift [dB]	-0.02	0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		84.1
Dist 3dB Peak [mm]		14.9



Measurement Report for Device, P51 LTE5_QPSK10M_Rear Face_1cm_Ch 20525_1RB_OS24

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 10.00	Band 5	LTE-FDD, 10175-CAH	836.500, 20525	9.70	0.891	40.4

Hardware Setup

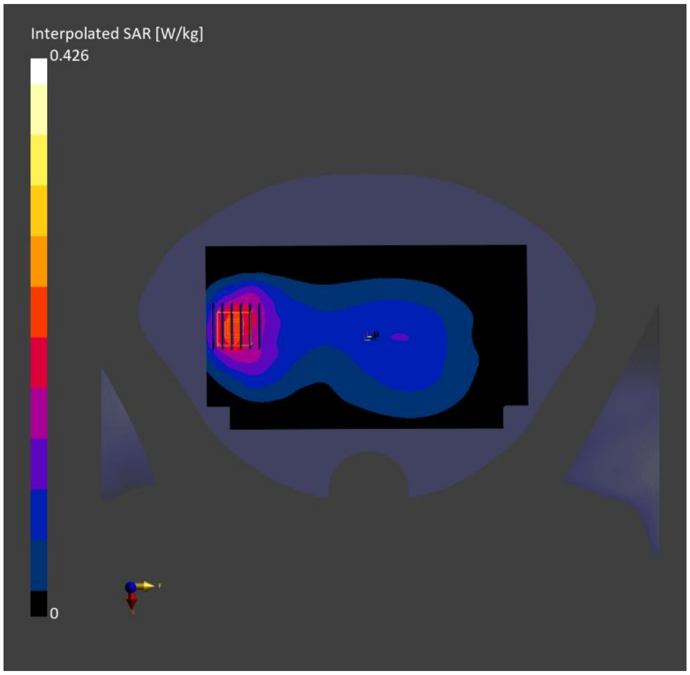
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-May-29	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-29	2025-05-29
psSAR1g [W/kg]	0.205	0.221
psSAR10g [W/kg]	0.134	0.129
Power Drift [dB]	-0.02	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		79.9
Dist 3dB Peak [mm]		13.2



Measurement Report for Device, P52 LTE7_QPSK20M_Rear Face_1cm_Ch 21100_1RB_OS99

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 10.00	Band 7	LTE-FDD, 10169-CAF	2535.000, 21100	7.64	1.85	39.8

Hardware Setup

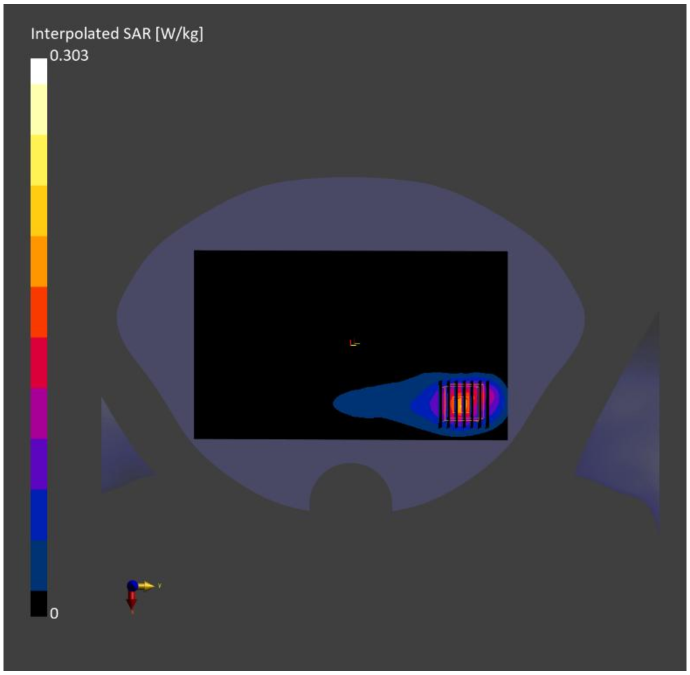
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-04	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-04	2025-06-04
psSAR1g [W/kg]	0.151	0.148
psSAR10g [W/kg]	0.072	0.069
Power Drift [dB]	-0.05	0.05
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		80.7
Dist 3dB Peak [mm]		10.2



Measurement Report for Device, P53 LTE12_QPSK10M_Rear Face_1cm_Ch 23060_1RB_OS24

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 10.00	Band 12	LTE-FDD, 10175-CAH	704.000, 23060	9.99	0.852	40.5

Hardware Setup

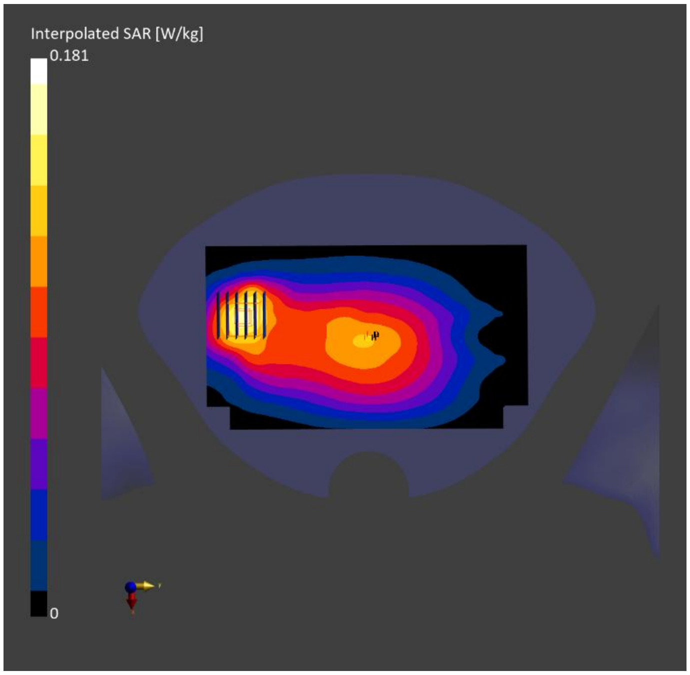
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-03	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-03	2025-06-03
psSAR1g [W/kg]	0.078	0.084
psSAR10g [W/kg]	0.053	0.049
Power Drift [dB]	-0.03	0.05
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		73.6
Dist 3dB Peak [mm]		13.0



Measurement Report for Device, P54 LTE41_QPSK20M_Rear Face_1cm_Ch 39750_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 10.00	Band 41	LTE-TDD, 10172-CAH	2506.000, 39750	7.64	1.83	39.8

Hardware Setup

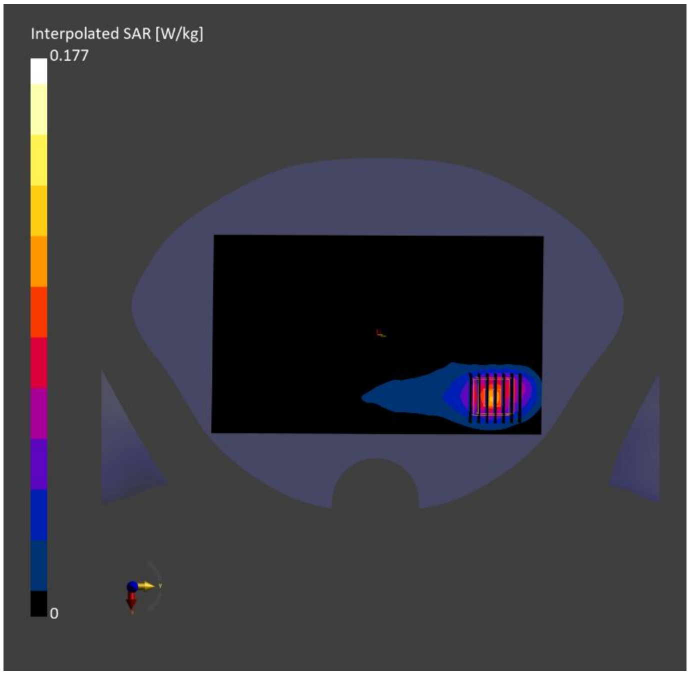
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-04	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-04	2025-06-04
psSAR1g [W/kg]	0.090	0.089
psSAR10g [W/kg]	0.043	0.041
Power Drift [dB]	0.12	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		81.7
Dist 3dB Peak [mm]		10.3



Measurement Report for Device, P55 N2_SCS15kHz_DFT-s-OFDM BPSK 20M_Bottom Side_1cm_Ch 376000_1RB_OS104

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	EDGE BOTTOM, 10.00	Band n2	5G NR FR1 FDD, 10931-AAC	1880.000, 376000	7.77	1.39	39.7

Hardware Setup

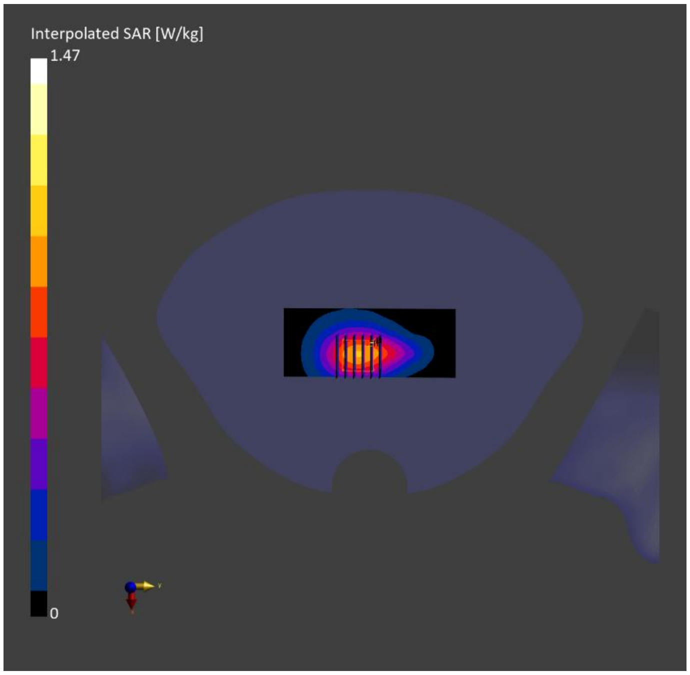
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-02	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	8.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-02	2025-06-02
psSAR1g [W/kg]	0.818	0.861
psSAR10g [W/kg]	0.472	0.511
Power Drift [dB]	-0.02	0.05
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		83.2
Dist 3dB Peak [mm]		14.5



Measurement Report for Device, P56 N5_SCS15kHz_DFT-s-OFDM BPSK 20M_Bottom Side_1cm_Ch 166800_1RB_OS1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	EDGE BOTTOM, 10.00	Band n5	5G NR FR1 FDD, 10931-AAC	834.000, 166800	9.70	0.890	40.4

Hardware Setup

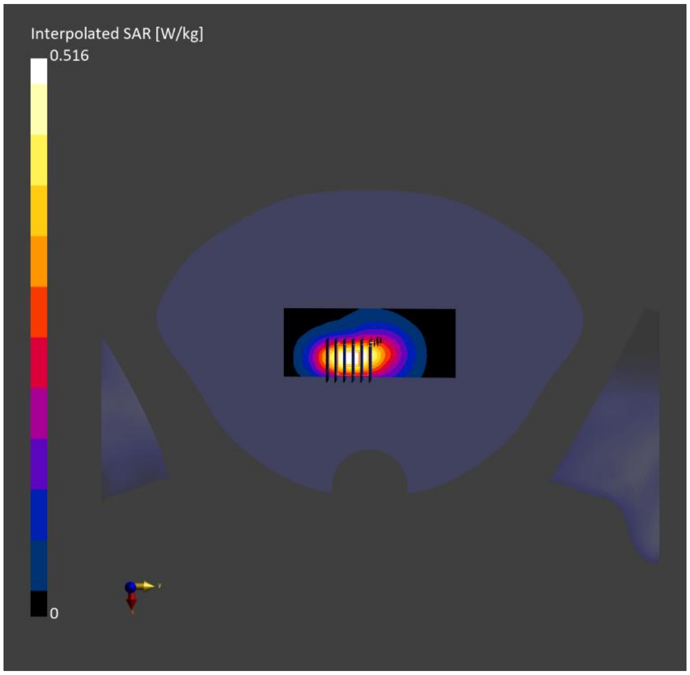
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-May-30	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	8.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-30	2025-05-30
psSAR1g [W/kg]	0.239	0.235
psSAR10g [W/kg]	0.143	0.126
Power Drift [dB]	-0.12	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		74.4
Dist 3dB Peak [mm]		9.7



Measurement Report for Device, P57 N7_SCS15kHz_DFT-s-OFDM BPSK 40M_Rear Face_1cm_Ch 507000_1RB_OS214

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 10.00	Band n7	5G NR FR1 FDD, 10934-AAC	2535.000, 507000	7.64	1.85	39.8

Hardware Setup

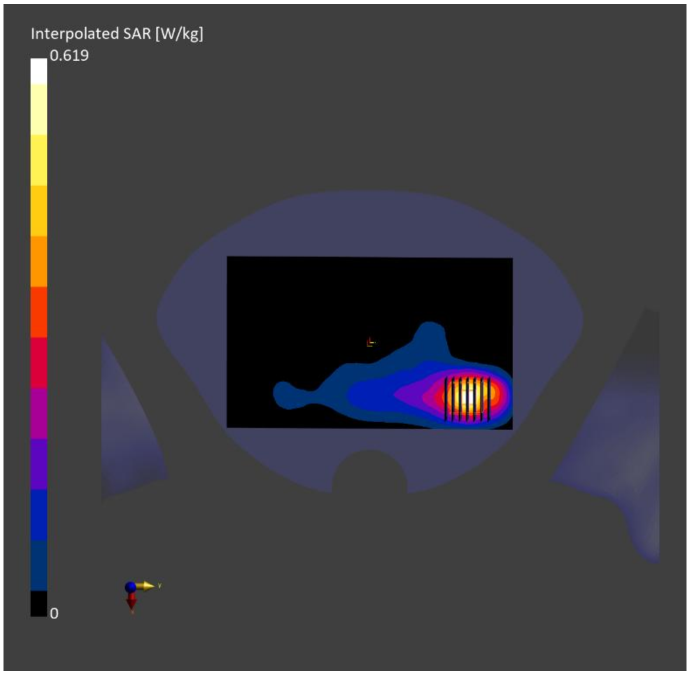
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-04	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-04	2025-06-04
psSAR1g [W/kg]	0.325	0.330
psSAR10g [W/kg]	0.162	0.166
Power Drift [dB]	-0.16	0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		82.9
Dist 3dB Peak [mm]		12.7



Measurement Report for Device, P58 N26_SCS15kHz_DFT-s-OFDM BPSK 20M_Bottom Side_1cm_Ch 167300_1RB_OS1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	EDGE BOTTOM, 10.00	Band n26	5G NR FR1 FDD, 10931-AAC	836.500, 167300	9.70	0.891	40.4

Hardware Setup

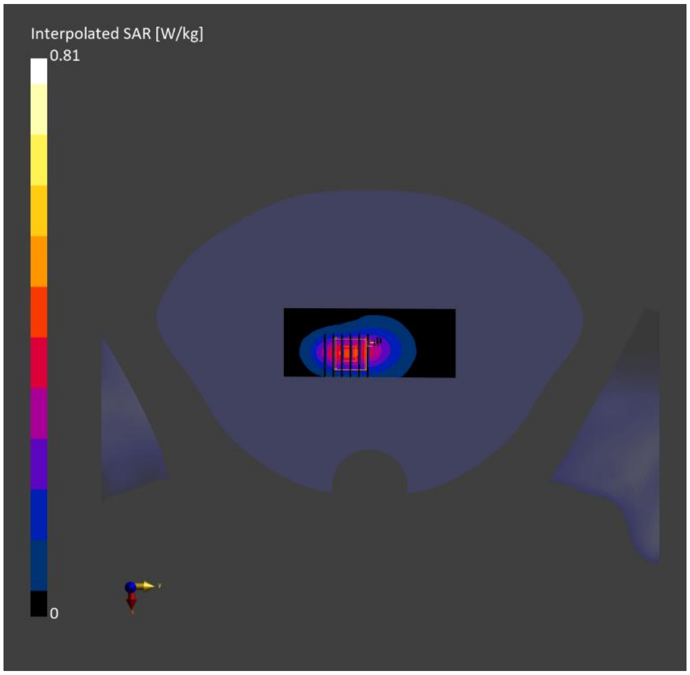
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-May-30	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	8.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-30	2025-05-30
psSAR1g [W/kg]	0.364	0.364
psSAR10g [W/kg]	0.215	0.195
Power Drift [dB]	0.00	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		73.4
Dist 3dB Peak [mm]		9.7



Measurement Report for Device, P59 N41_SCS30kHz_DFT-s-OFDM BPSK 100M_Rear Face_1cm_Ch 518598_135RB_OS138

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 10.00	Band n41	5G NR FR1 TDD, 10917-AAD	2592.990, 518598	7.64	1.89	39.7

Hardware Setup

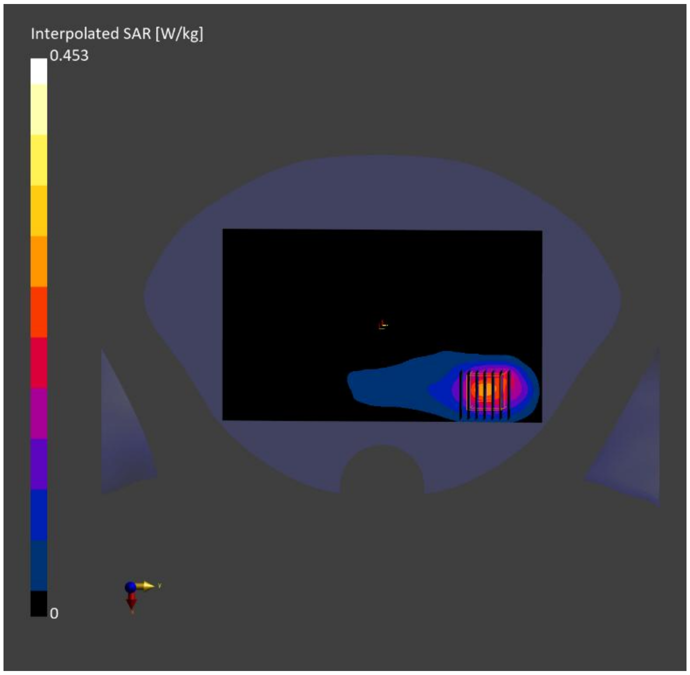
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-04	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-04	2025-06-04
psSAR1g [W/kg]	0.225	0.228
psSAR10g [W/kg]	0.115	0.110
Power Drift [dB]	0.13	0.29
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		81.4
Dist 3dB Peak [mm]		12.1



Measurement Report for Device, P60 N66_SCS15kHz_DFT-s-OFDM BPSK 20M_Bottom Side_1cm_Ch 349000_1RB_OS104

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	EDGE BOTTOM, 10.00	Band n66	5G NR FR1 FDD, 10931-AAC	1745.000, 349000	8.40	1.32	40.0

Hardware Setup

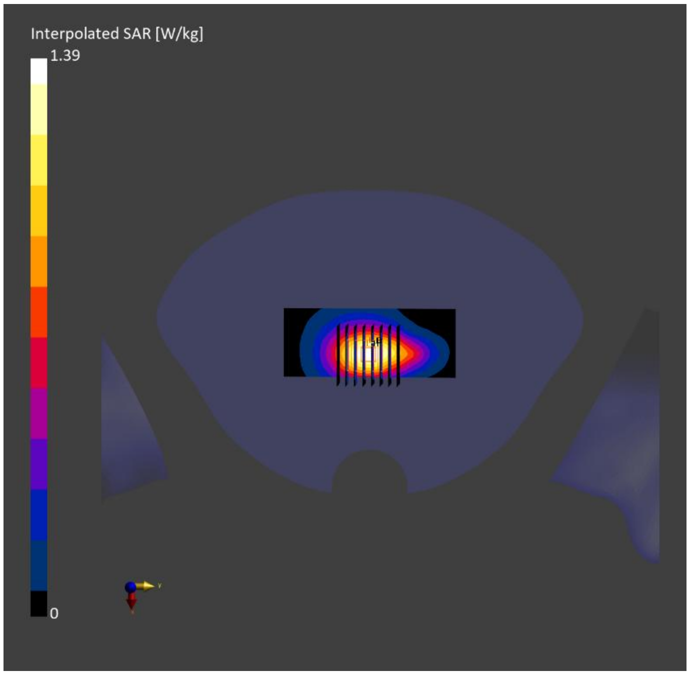
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-03	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	8.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-03	2025-06-03
psSAR1g [W/kg]	0.799	0.794
psSAR10g [W/kg]	0.466	0.483
Power Drift [dB]	-0.05	N/A
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		83.5
Dist 3dB Peak [mm]		4.8



Measurement Report for Device, P61 N77_SCS30kHz_DFT-s-OFDM BPSK 100M_Rear Face_1cm_Ch 656667_135RB_OS69

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 10.00	Band n77	5G NR FR1 TDD, 10917-AAD	3850.005, 656667	6.75	3.26	37.1

Hardware Setup

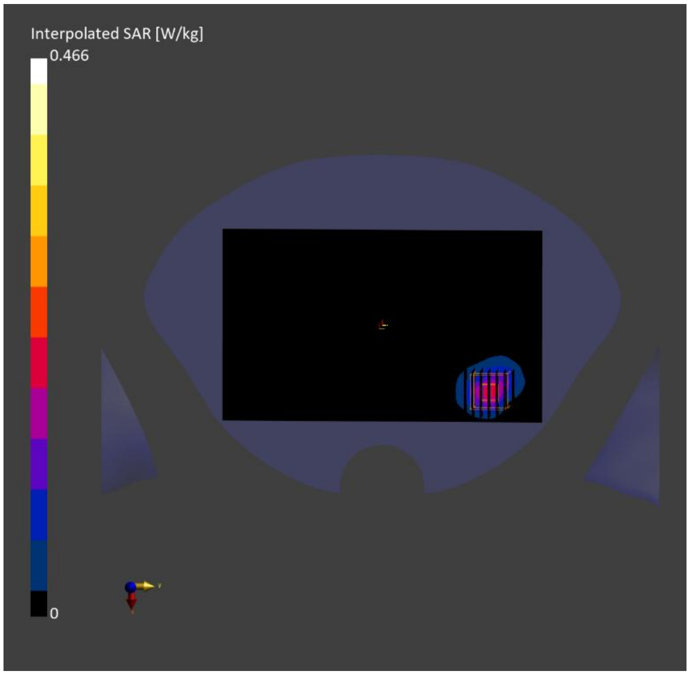
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-05	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	28.0 x 28.0 x 28.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-05	2025-06-05
psSAR1g [W/kg]	0.160	0.171
psSAR10g [W/kg]	0.063	0.064
Power Drift [dB]	0.73	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		74.0
Dist 3dB Peak [mm]		8.5



Measurement Report for Device, P62 N77_SCS30kHz_DFT-s-OFDM BPSK 100M_Rear Face_1cm_Ch 662000_135RB_OS69

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 10.00	Band n77	5G NR FR1 TDD, 10917-AAD	3930.000, 662000	6.75	3.44	37.0

Hardware Setup

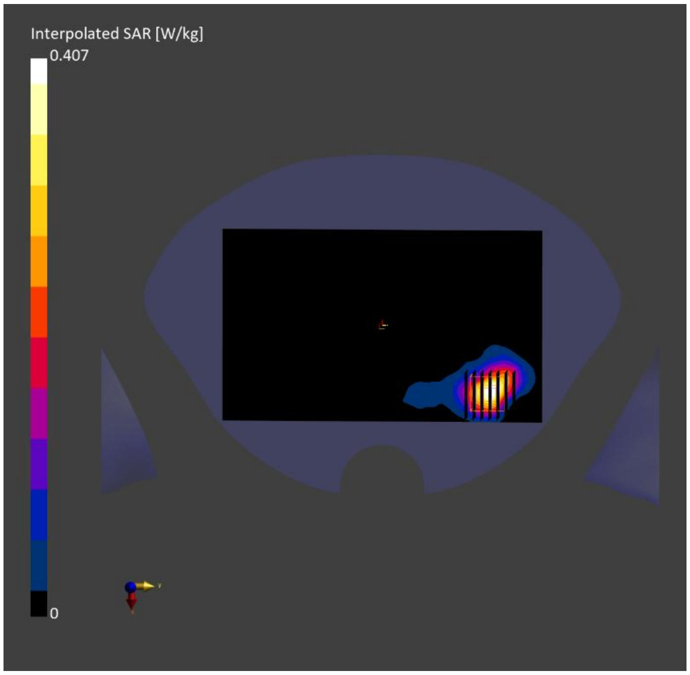
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-05	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	28.0 x 28.0 x 28.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-05	2025-06-05
psSAR1g [W/kg]	0.138	0.146
psSAR10g [W/kg]	0.055	0.054
Power Drift [dB]	0.07	0.06
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		72.9
Dist 3dB Peak [mm]		7.9



Measurement Report for Device, P63 802.11b_Rear Face_1cm_Ch1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	BACK, 10.00	WLAN 2.4GHz	WLAN, 10012-CAB	2412.000, 1	7.6	1.76	39.9

Hardware Setup

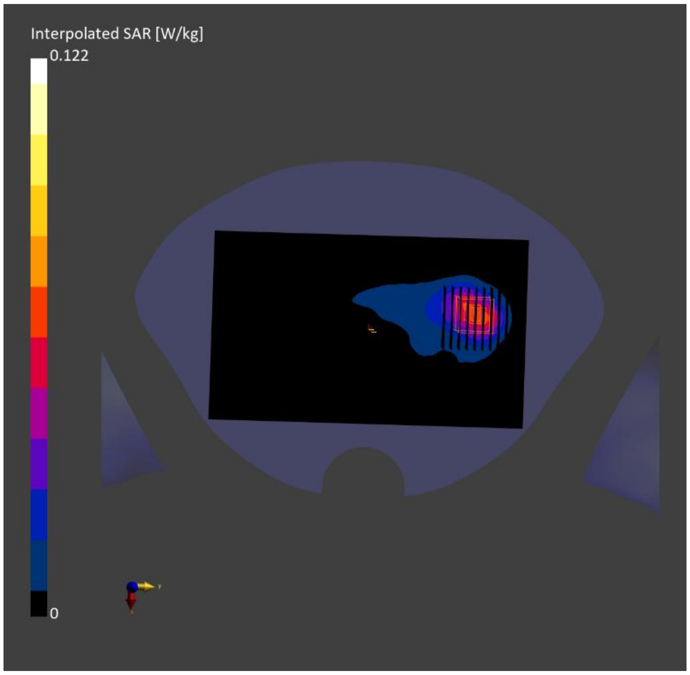
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-06	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-06	2025-06-06
psSAR1g [W/kg]	0.054	0.055
psSAR10g [W/kg]	0.028	0.027
Power Drift [dB]	-0.04	0.07
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		75.1
Dist 3dB Peak [mm]		10.9



Measurement Report for Device, P64 802.11a_Top Side_1cm_Ch 48

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	EDGE TOP, 10.00	U-NII-1, U-NII-2A	WLAN, 10317-AAE	5240.000, 48	5.45	4.55	37.5

Hardware Setup

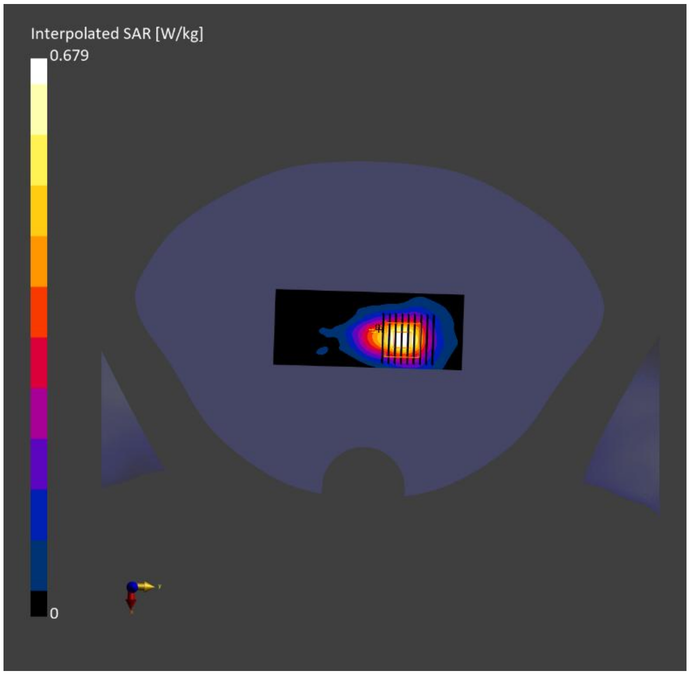
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-06	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	8.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-06	2025-06-06
psSAR1g [W/kg]	0.214	0.221
psSAR10g [W/kg]	0.084	0.084
Power Drift [dB]	0.60	-0.11
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		69.0
Dist 3dB Peak [mm]		10.6



Measurement Report for Device, P65 802.11a_Front Face_1cm_Ch 149

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	FRONT, 10.00	U-NII-2C, U-NII-3	WLAN, 10317-AAE	5745.000, 149	4.98	5.10	36.6

Hardware Setup

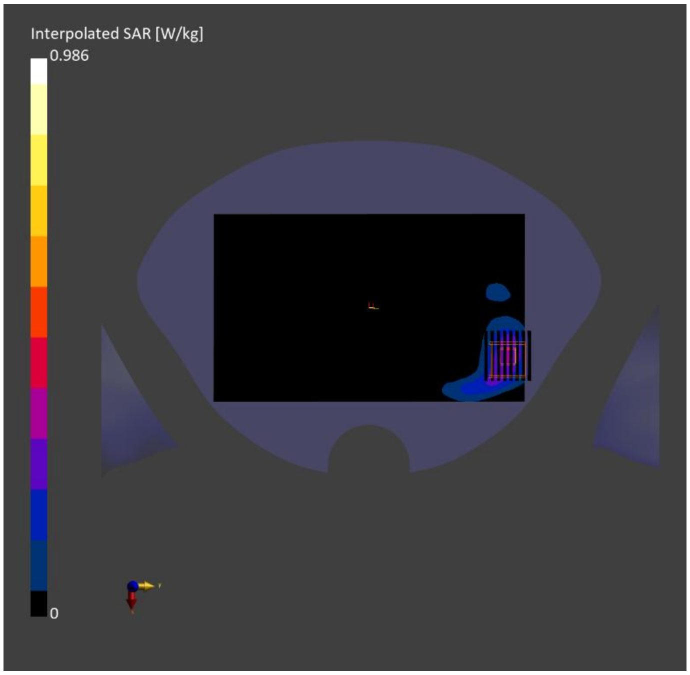
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-06	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-06	2025-06-06
psSAR1g [W/kg]	0.257	0.267
psSAR10g [W/kg]	0.106	0.100
Power Drift [dB]	-0.02	0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		61.3
Dist 3dB Peak [mm]		12.2



Measurement Report for Device, P66 BT_3DH5_Front Face_1cm_Ch 78

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 77.0 x 8.0		Mobile Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, HSL	FRONT, 10.00	Custom Band	CW, 10038-CAA	2480.000, 2480000	7.6	1.81	39.9

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2097	HSL600-10000, 2025-Jun-06	EX3DV4 - SN7628, 2024-07-03	DAE4 Sn1557, 2024-10-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-06	2025-06-06
psSAR1g [W/kg]	0.012	0.011
psSAR10g [W/kg]	0.006	0.005
Power Drift [dB]	0.08	0.05
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		66.8
Dist 3dB Peak [mm]		6.8